



S J P N Trust's

Hirasugar Institute of Technology, Nidasoshi.

Inculcating Values, Promoting Prosperity

Approved by AICTE, Recognized by Govt. of Karnataka and Affiliated to VTU Belagavi

ECE Dept.

**VLSI
DESIGN**

VI Sem

2017-18

Department of Electronics & Communication Engg.

Course : VLSI DESIGN-15EC63.

Sem.: 6th

Course Coordinator:

Prof. S. S. Kamate

Module 2



CIRCUIT DESIGN PROCESSES

Specification



Design



Manufacturing



VLSI



Test



PASS

Shipment



fault



FAIL

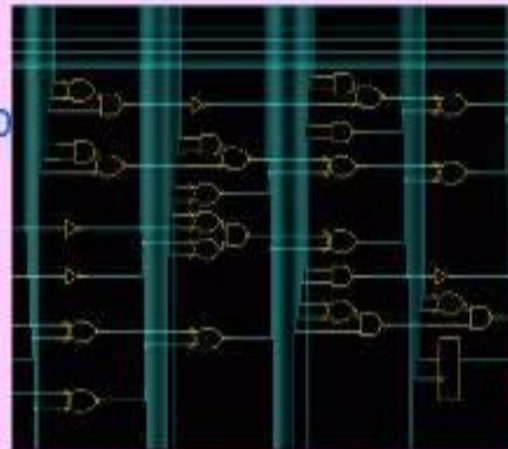
seed binning
repair or discard

Hardware Description Language

```
.....
.....
C <= A + B;
If(C>D)then
.....
- - - - -
.....
```

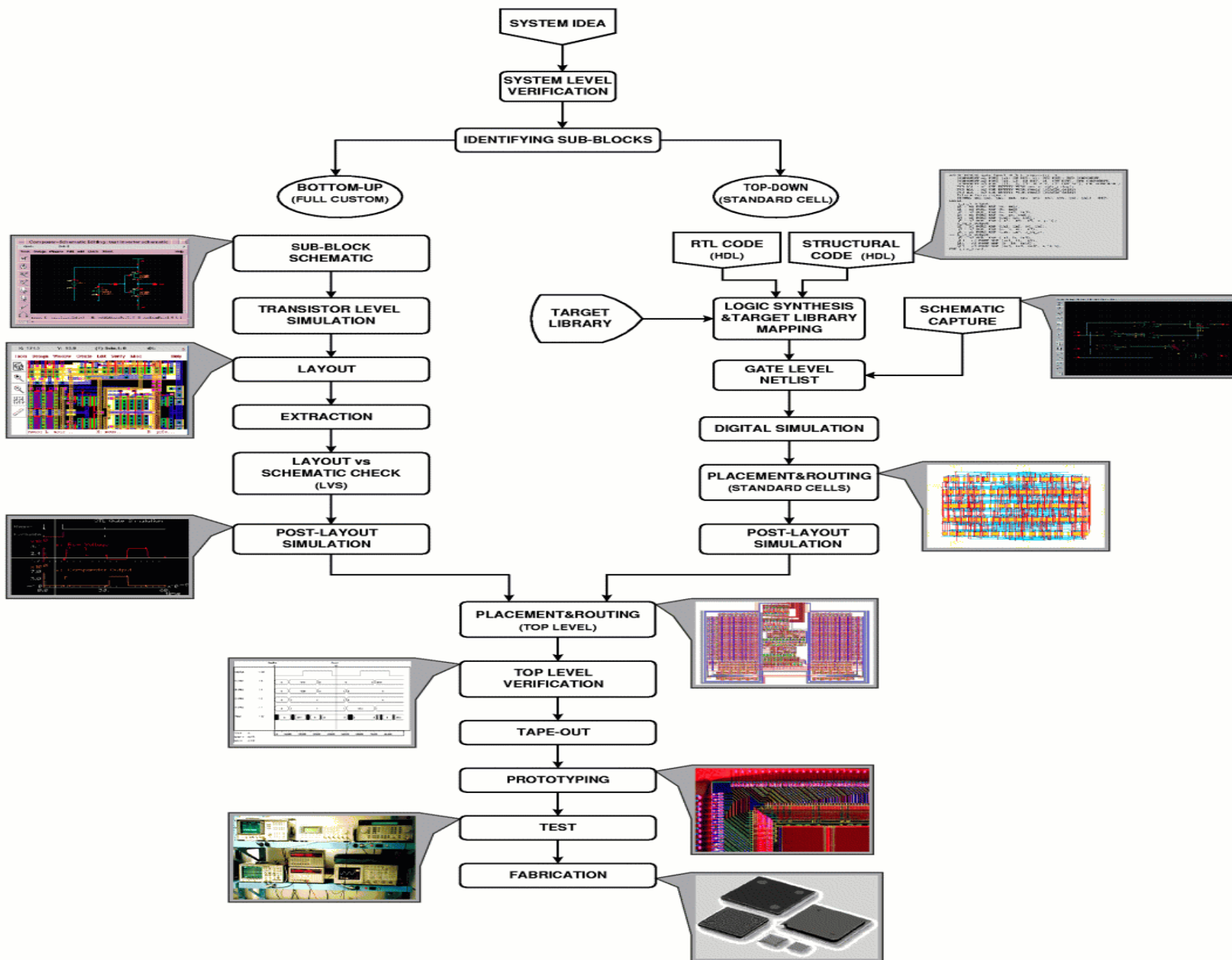
Circuit Description

VLSI CAD

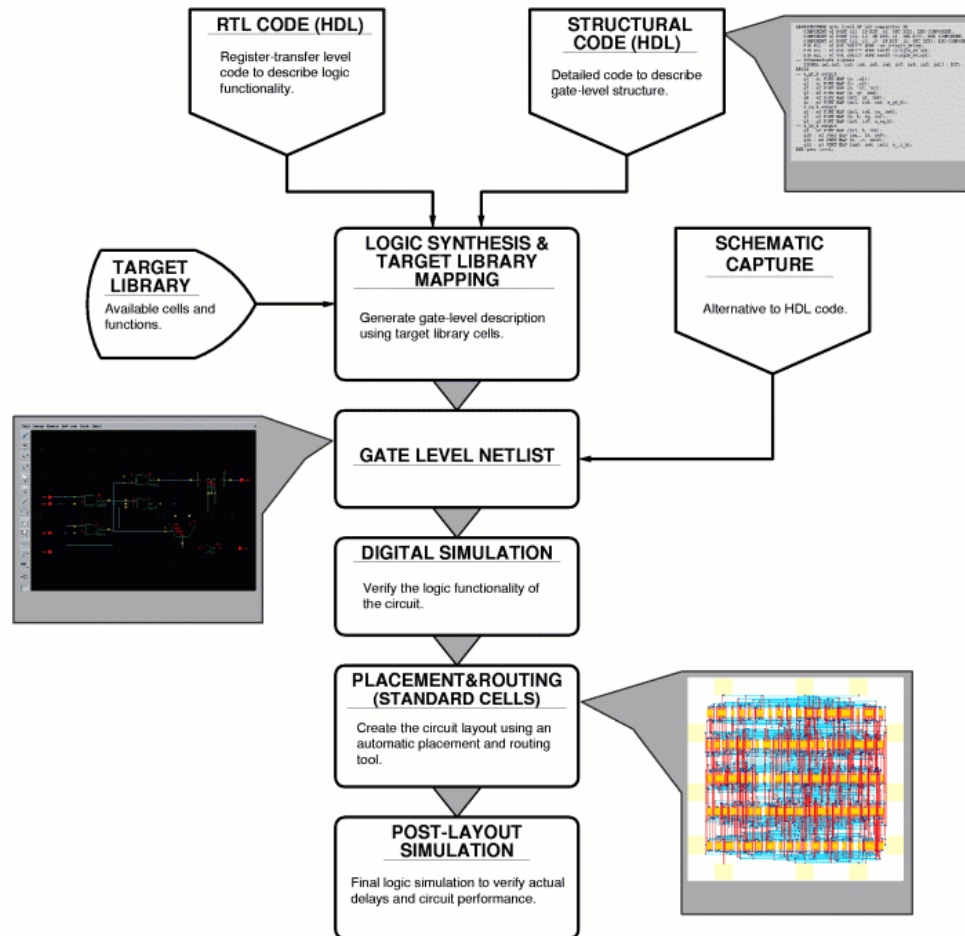


Circuit Schematic

VLSI DESIGN FLOW



TOP-DOWN (STANDARD CELL) DESIGN METHODOLOGY



BOTTOM-UP (FULL CUSTOM) DESIGN METHODOLOGY



SUB-BLOCK SCHEMATIC

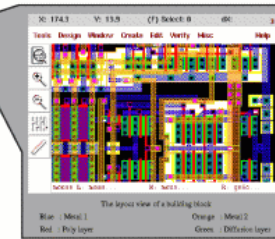
Transistor-level schematic drawings of the circuit blocks are created in Schematic Editor.

TRANSISTOR LEVEL SIMULATION

SPICE(or equivalent) simulation of circuit blocks is used to verify their functionality.

LAYOUT

Mask-layout of all circuit blocks are created in Layout Editor.



EXTRACTION

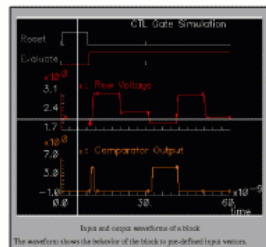
Actual device dimensions and parasitic parameters are determined from mask layout.

LAYOUT vs SCHEMATIC CHECK (LVS)

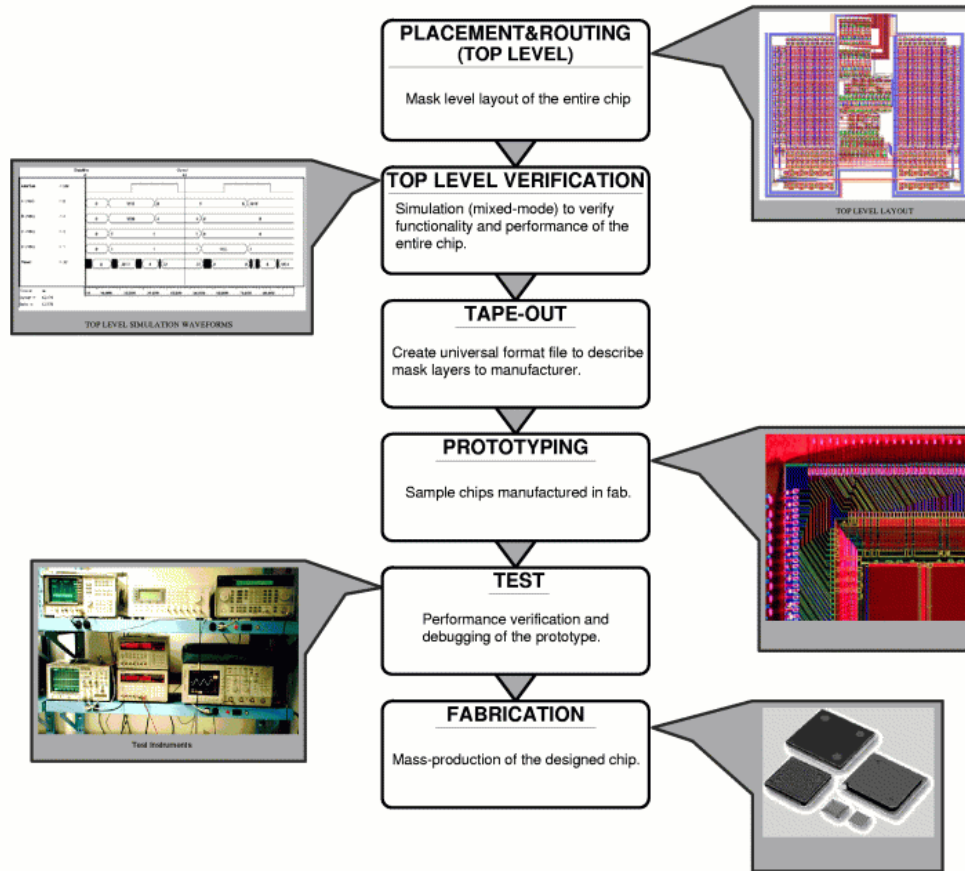
Automatic comparison of mask layout and circuit schematic.

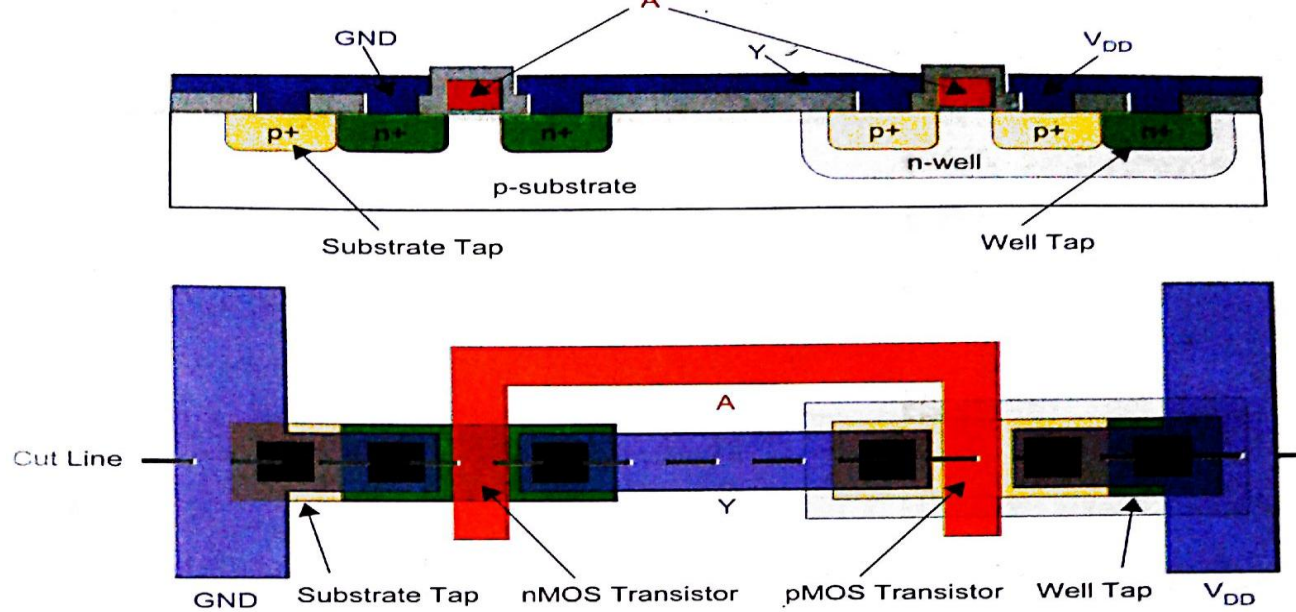
POST-LAYOUT SIMULATION

Final SPICE simulation of the circuit of the circuit blocks using extracted parameters.



FROM MASK LAYOUT TO FABRICATED CHIP





Figs 1.34–1.35(a) Inverter Cross-Section and Top View

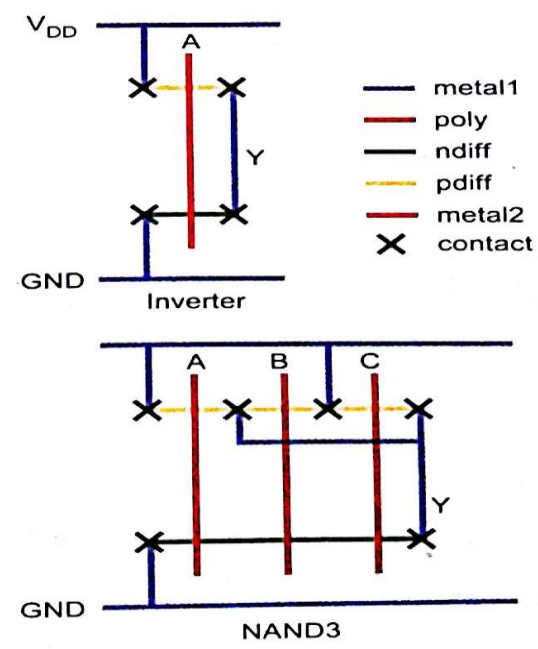


Fig 1.43 Stick Diagrams

✓ MOS designs are used for making masks for fabrication.

✓ MOS circuits consists of four basic layers

n-diffusion

p-diffusion

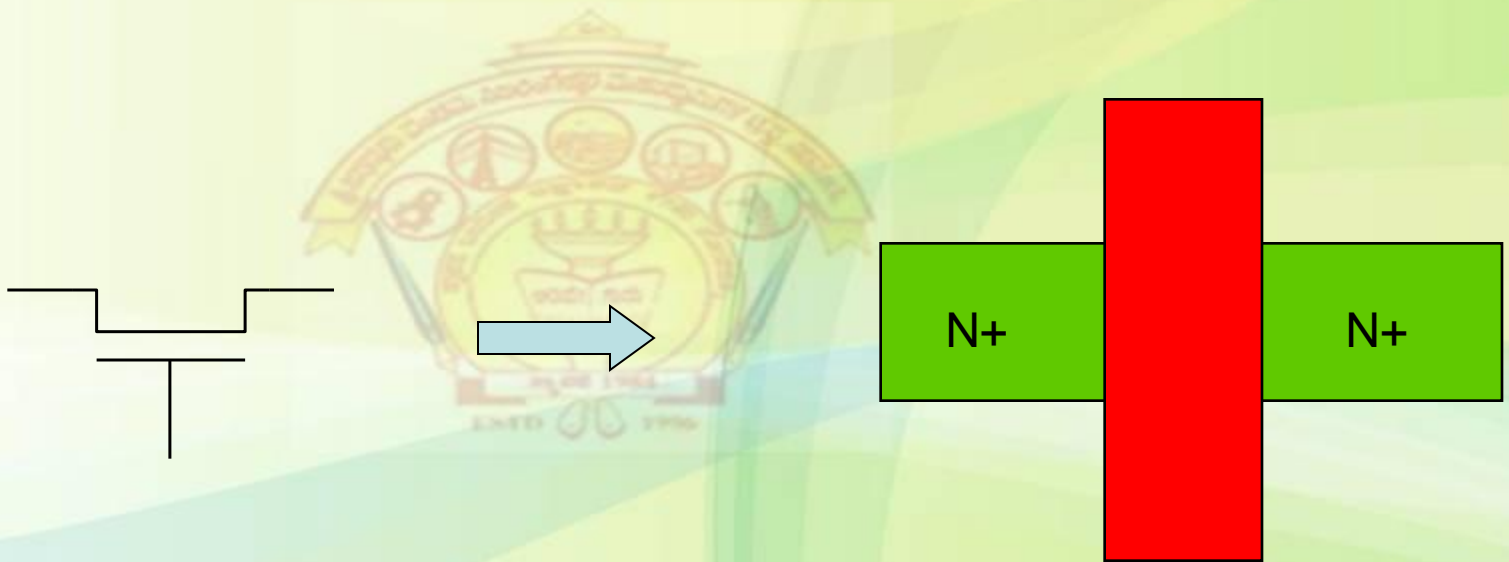
polysilicon

metal

✓ Stick diagram hides lower level circuit details and electrical parameters such as **current, speed and noise**, but comes one step closer to actual layout.

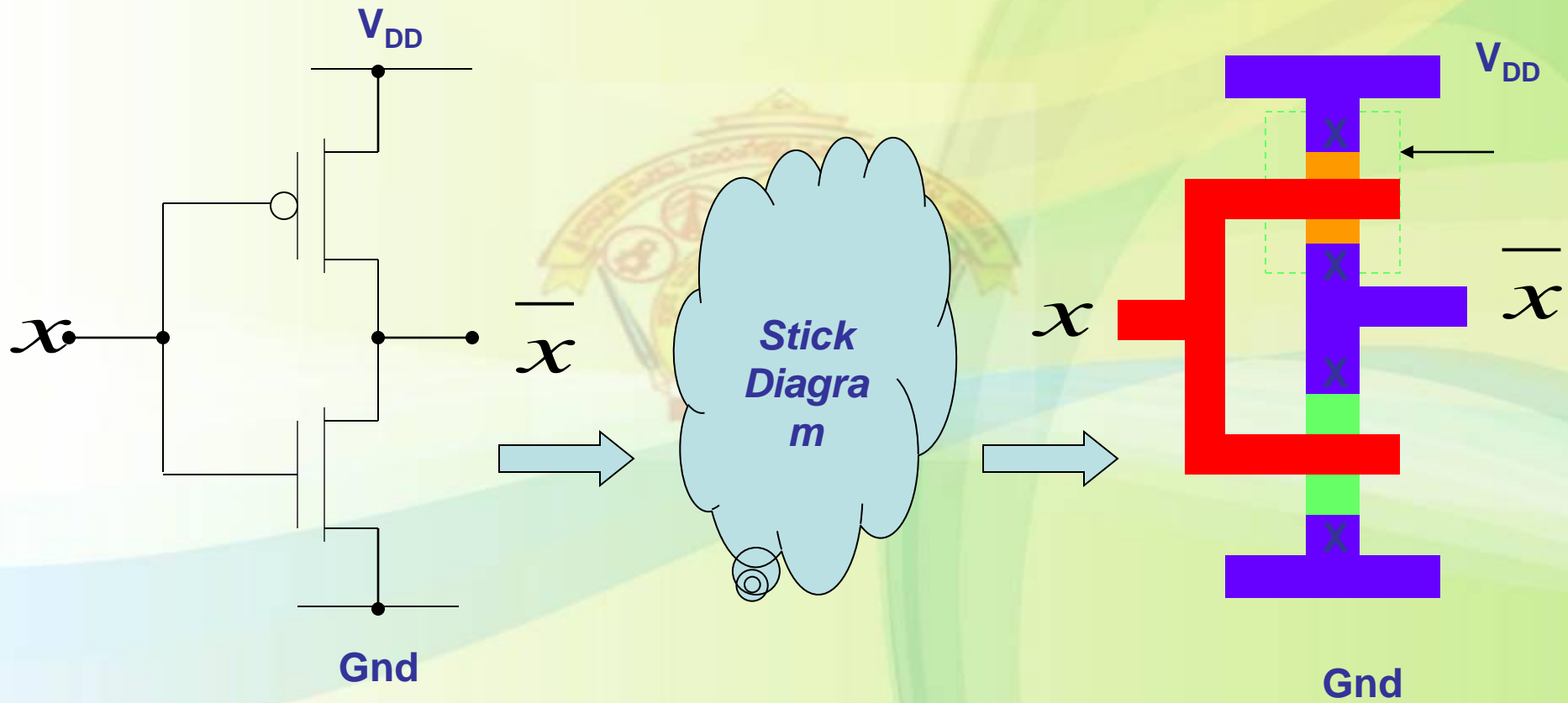
✓ One of the fundamental difficulties in specifying design rules is that the fabrication processes are undergoing rapid evolutionary changes.

Stick Diagrams

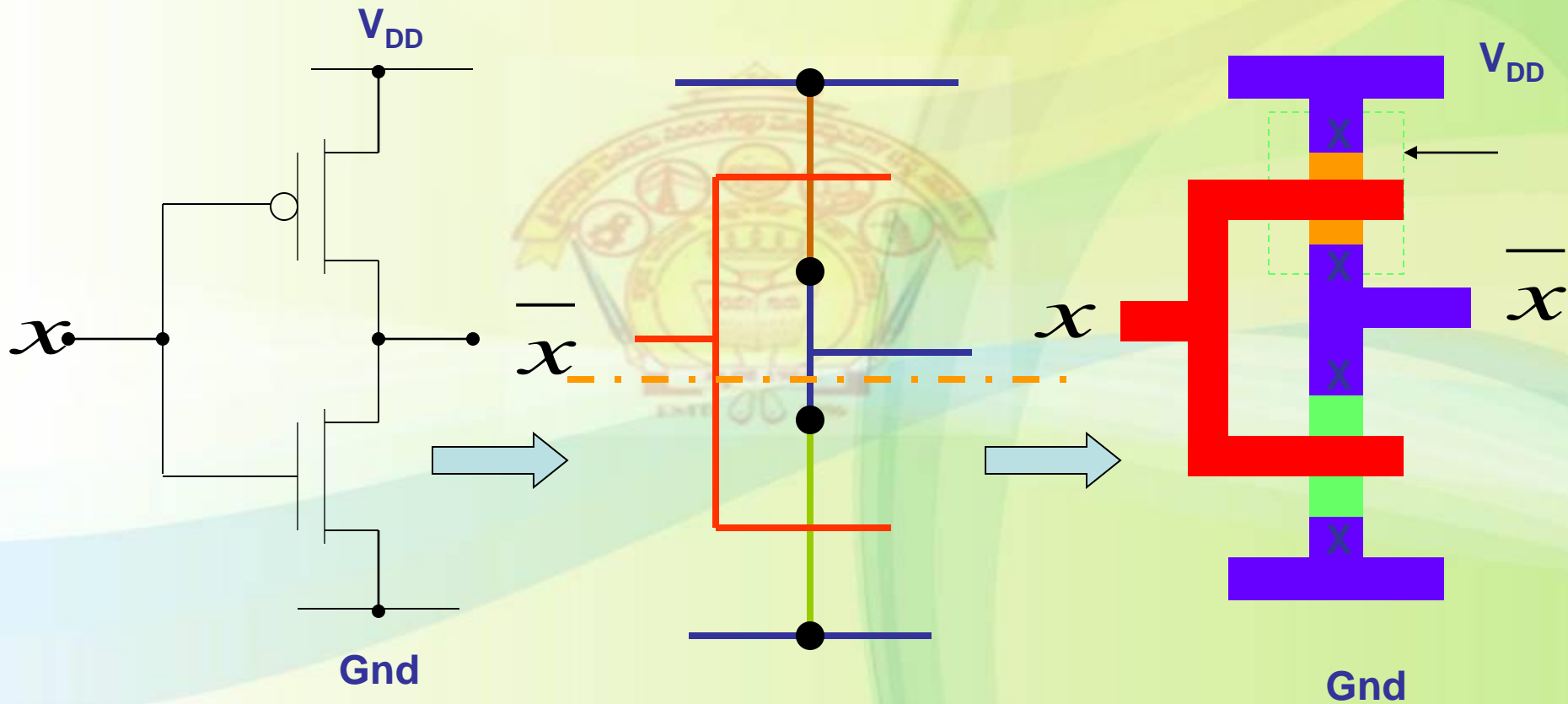


Stick diagrams are used to convey layer information through the use of color code

Stick Diagrams



Stick Diagrams



Stick Diagrams

- VLSI design aims to translate circuit concepts onto silicon.
- stick diagrams are a means of capturing topography and layer information using simple diagrams.
- Stick diagrams convey layer information through colour codes (or monochrome encoding).
- Acts as an interface between symbolic circuit and the actual layout.

Stick Diagrams

- Does show all components/vias.
- It shows relative placement of components.
- Goes one step closer to the layout
- Helps plan the layout and routing

A stick diagram is a cartoon of a layout.

Stick Diagrams

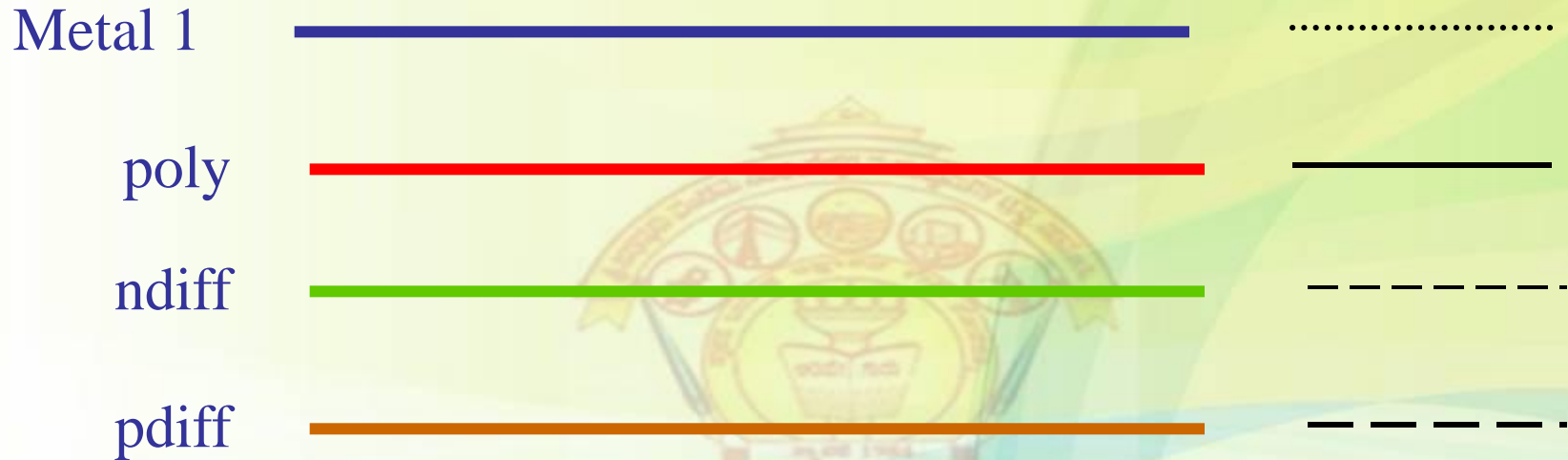
- Does *not* show
 - Exact placement of components
 - Transistor sizes
 - Wire lengths, wire widths, tub boundaries.
 - Any other low level details such as parasitics..

Stick Diagrams

- Does *not* show
 - Exact placement of components
 - Transistor sizes
 - Wire lengths, wire widths, tub boundaries.
 - Any other low level details such as parasitics..



Stick Diagrams – Notations



Can also draw
in shades of
gray/line style.

Similarly for contacts, via, tub etc..

Stick Diagrams – Some rules

Rule 1.

When two or more 'sticks' of the same type cross or touch each other that represents electrical contact.



Stick Diagrams – Some rules

Rule 2.

When two or more ‘sticks’ of different type cross or touch each other there is no electrical contact.

(If electrical contact is needed we have to show the connection explicitly).



Stick Diagrams – Some rules

Rule 3.

When a poly crosses diffusion it represents a transistor.

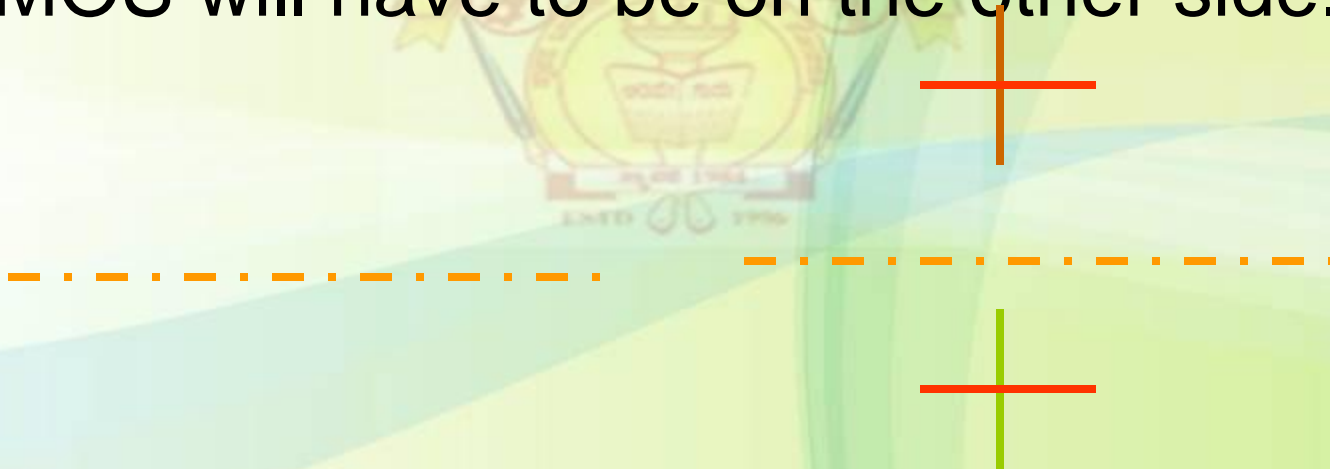


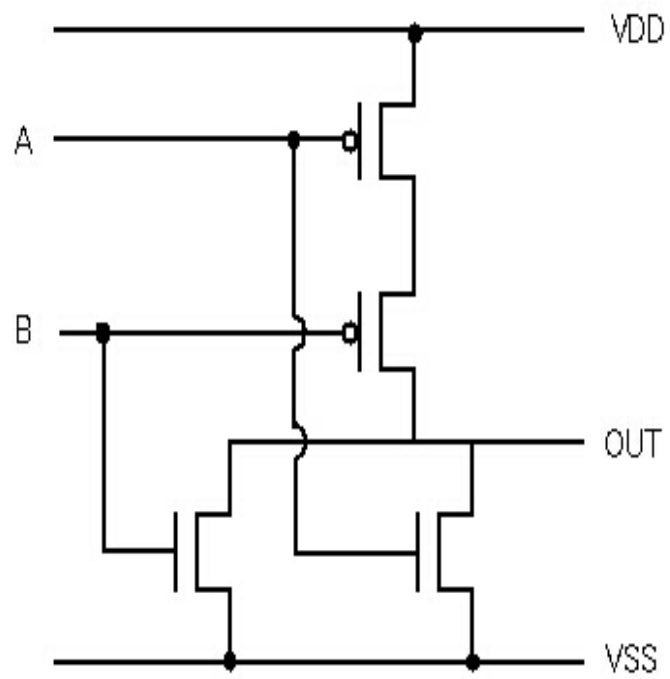
Note: If a contact is shown then it is **not** a transistor.

Stick Diagrams – Some rules

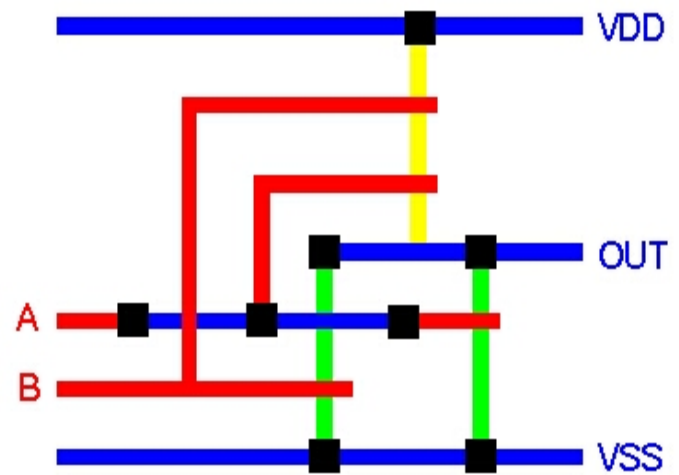
Rule 4.

In CMOS a demarcation line is drawn to avoid touching of p-diff with n-diff. All pMOS must lie on one side of the line and all nMOS will have to be on the other side.

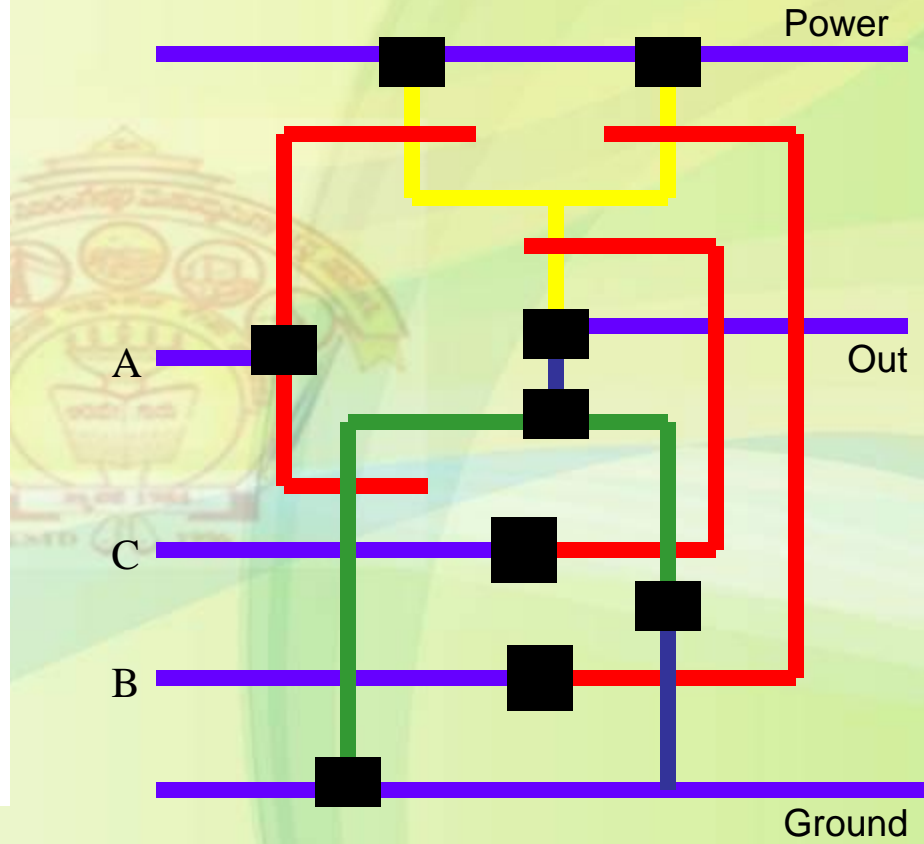
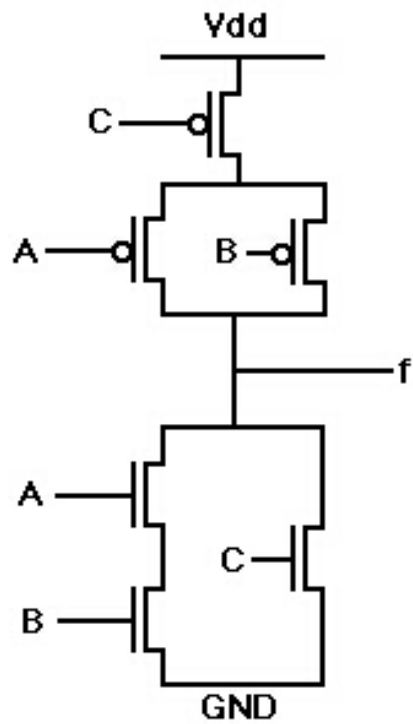




NOR gate in CMOS



Example: $f = \overline{(A \cdot B) + C}$



Stick Diagrams

- Summary:
 - What is stick diagram?
 - Why stick diagram?
 - Conventions and rules related to stick diagram.
 - Drawing stick diagrams.

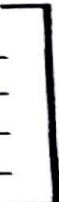

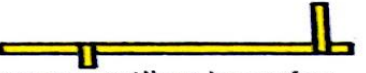

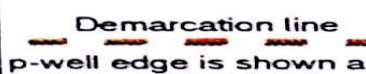




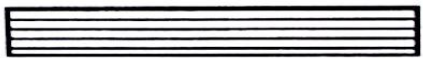

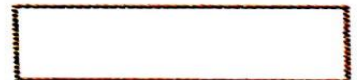

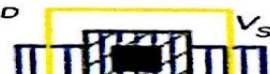
Stick Diagrams




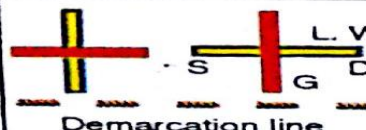

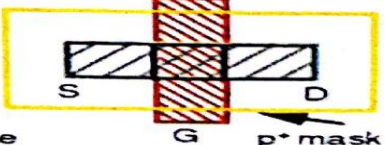
- **Home work:**
 1. Draw the stick diagram for two input CMOS NAND gate.
 2. Draw the stick diagram for two input NAND gate using NMOS Logic.
 3. Draw the stick diagram for 2:1 MUX using
 - a) Pass transistors
 - b) Transmission gates.

Drawing stick diagram is truly Fun!!. Enjoy it.

COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER
GREEN		n-diffusion (n+ active) Thinox*		ND
RED		Polysilicon		NP
BLUE		Metal 1		NM
BLACK		Contact cut		NC
GRAY	NOT APPLICABLE	Overglass		NG
nMOS ONLY YELLOW		Implant		NI
nMOS ONLY BROWN		Buried contact		NB
FEATURE	FEATURE (STICK)	FEATURE (SYMBOL)	FEATURE (MASK)	
n-type enhancement mode transistor				
Transistor length to width ratio L:W should be shown.				
n-type depletion mode transistor nMOS only				
Source, drain and gate labelling will not normally be shown.				

COLOR PLATE 1(a) Encodings for a simple single metal nMOS process. (See Figure 3.1(a) for nMOS monochrome encoding details.)

COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER
GREEN RED BLUE BLACK GRAY	 <p>Encoding as in Color plate 1 (a)</p>	n-diffusion (n ⁺ active) Thinox*	 <p>* Thinox = n-diff. + p-diff. + transistor channels</p> <p>Encoding as in Color plate 1 (a)</p>	CAA or CNA CPF CMF CC COG
		Polysilicon Metal 1 Contact cut Overglass		
YELLOW (STICK) YELLOW DARK BLUE OR PURPLE BLACK BROWN BLACK	 <p>green outline here for clarity</p>  <p>Not shown on diagram</p>  <p>Demarcation line p-well edge is shown as a demarcation line in stick diagrams</p> 	p-diffusion (p ⁺ active) p ⁺ mask Metal 2 VIA p-well V _{DD} or V _{SS} contact	  <p>either or</p>      	CAA or CPA CPP CMS CVA CPW CC

FEATURE	FEATURE (STICK)	FEATURE (SYMBOL)	FEATURE (MASK)
n-type enhancement mode transistor (as in Color plate 1 (a)) Transistor length to width ratio L:W may be shown.	 <p>Demarcation line</p> <p>L:W</p>		
p-type enhancement mode transistor Note: p-type transistors are placed above and n-type below the demarcation line	 <p>Demarcation line</p> <p>S G D</p> <p>L:W</p>	 <p>S G D</p>	 <p>S G D</p> <p>G p⁺ mask</p>

COLOR PLATE 1(b)

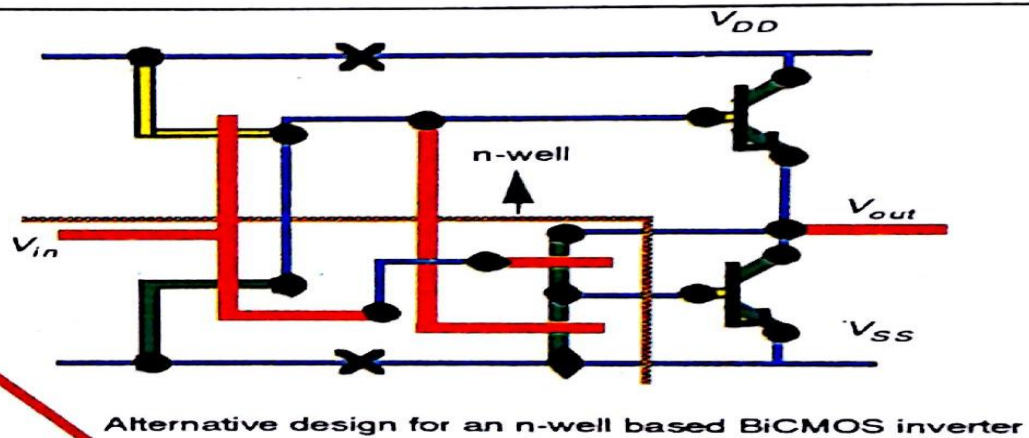
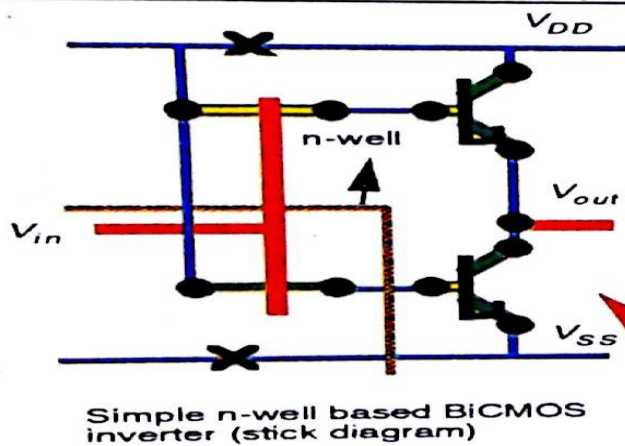
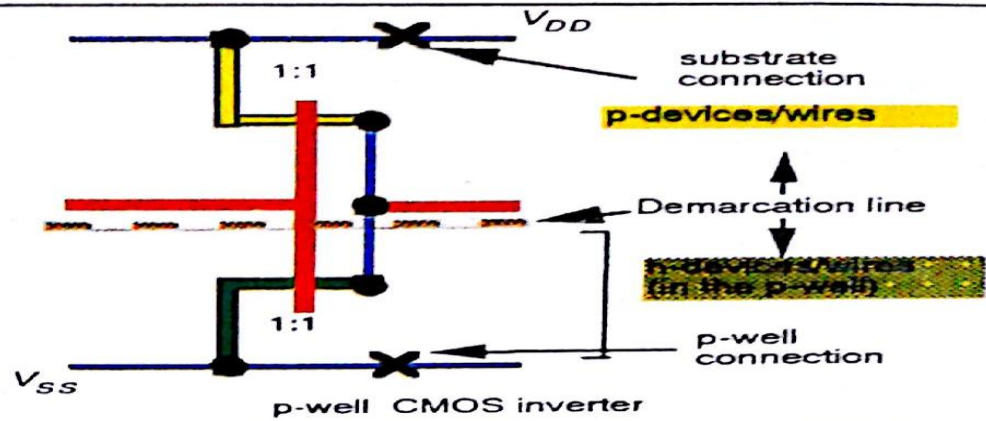
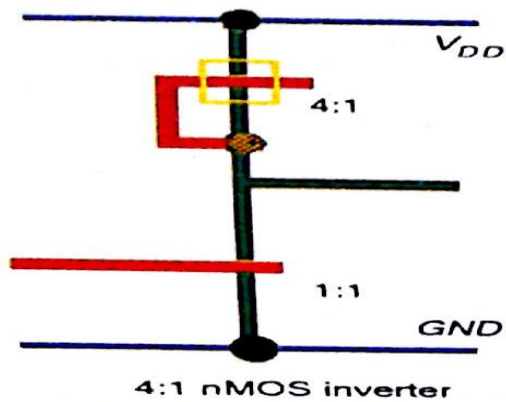
Color encodings for a double metal CMOS p-well process. The same well encoding and demarcation line is used for an n-well process. For a p-well process, the n features are in the well. For an n-well process, the p features are in the well. (See Figure 3.1(b) for CMOS monochrome encoding details.)

COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER
ORANGE		Polysilicon 2		CPS
		Bipolar npn transistor	See Color plate 6 also Figure 3.13(f)	Not applicable
PINK	Not separately encoded	p-base of bipolar npn transistor		CBA
PALE GREEN	Not separately encoded	Buried collector of bipolar npn transistor		CCA

FEATURE	FEATURE (STICK)	FEATURE (SYMBOL)	FEATURE (MASK)
<i>n</i> -type enhancement poly. 2 transistor.	<p>Demarcation line</p> <p>L: W</p> <p>S G D</p>	<p>S G D</p>	<p>S G D</p>
Transistor length to width ratio L: W may be shown.			
<i>p</i> -type enhancement poly. 2 transistor	<p>L: W</p> <p>S G D</p> <p>Demarcation line</p>	<p>S G D</p>	<p>S G D</p>
Note: <i>p</i> -type transistors are placed above and <i>n</i> -type below the demarcation line			
<i>n</i> pn bipolar transistor			See Figure 3.13(f) and Color plate 6

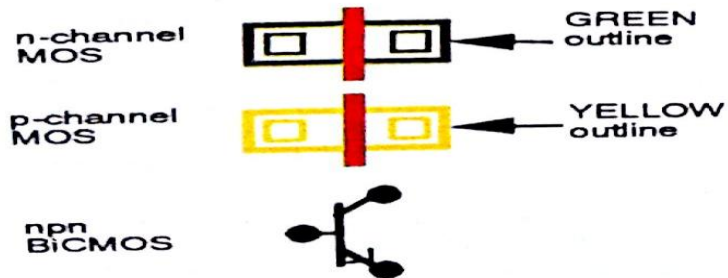
COLOR PLATE 1(c)

Additional encodings for a double metal double poly. BiCMOS n-well process. The same well encoding and demarcation line as in Figure 3.1(b) is used for an n-well process. For a p-well process, the n features are in the well. (See Color plate 6 for additional BiCMOS color encoding details and see Figure 3.13(f) for correct CIF encoding details).

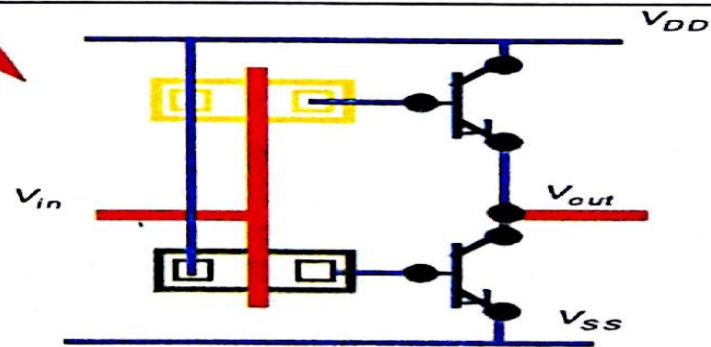


Simple symbolic notation

Transistors

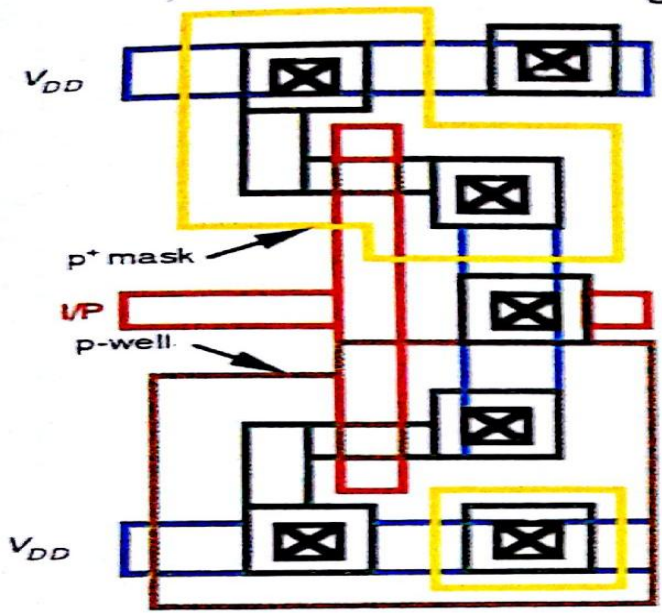


WIRES etc., as for stick diagrams

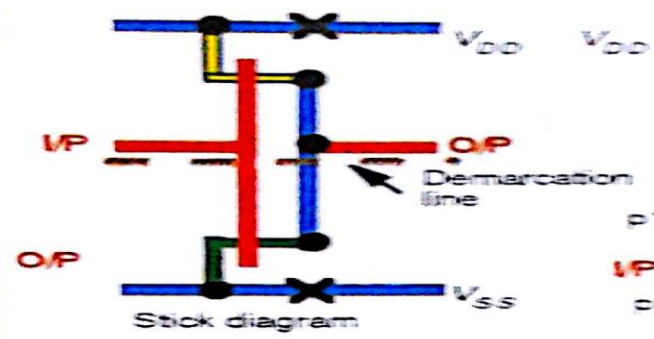


COLOR PLATE 1(d) Color stick diagram examples. (See Figure 3.1(d) monochrome stick diagrams and simple symbolic encoding.)

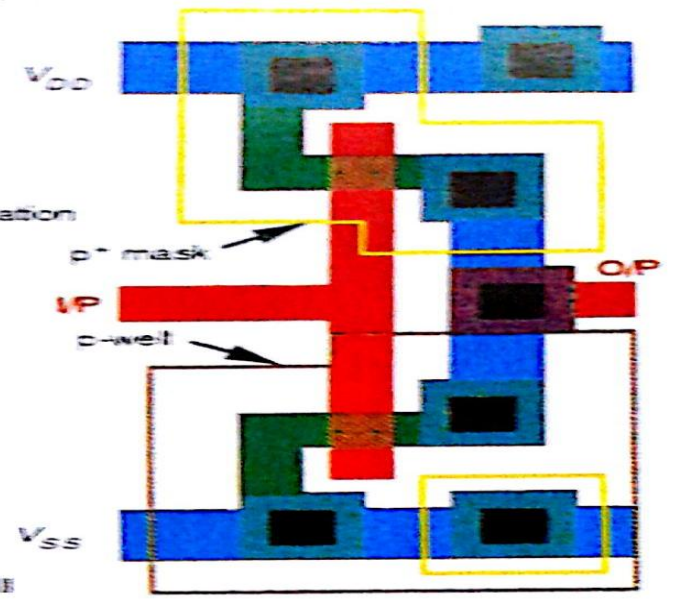
CMOS inverter I/P & O/P on polysilicon



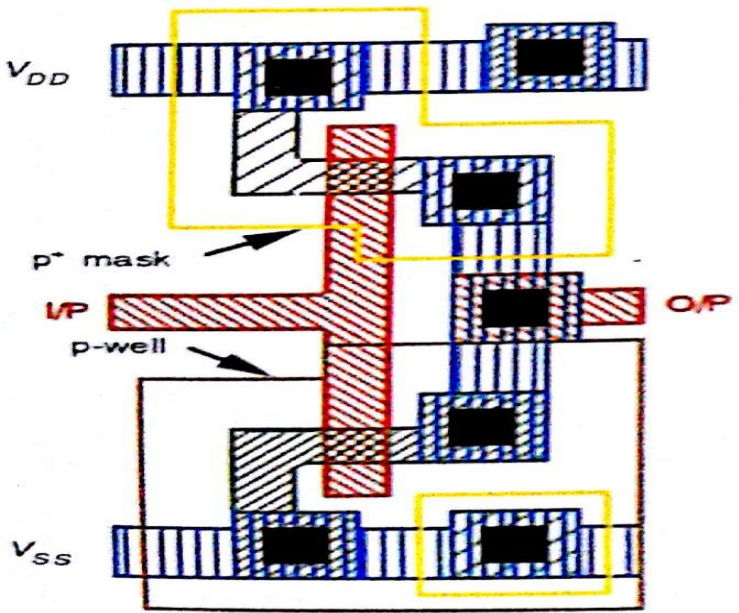
Color outline



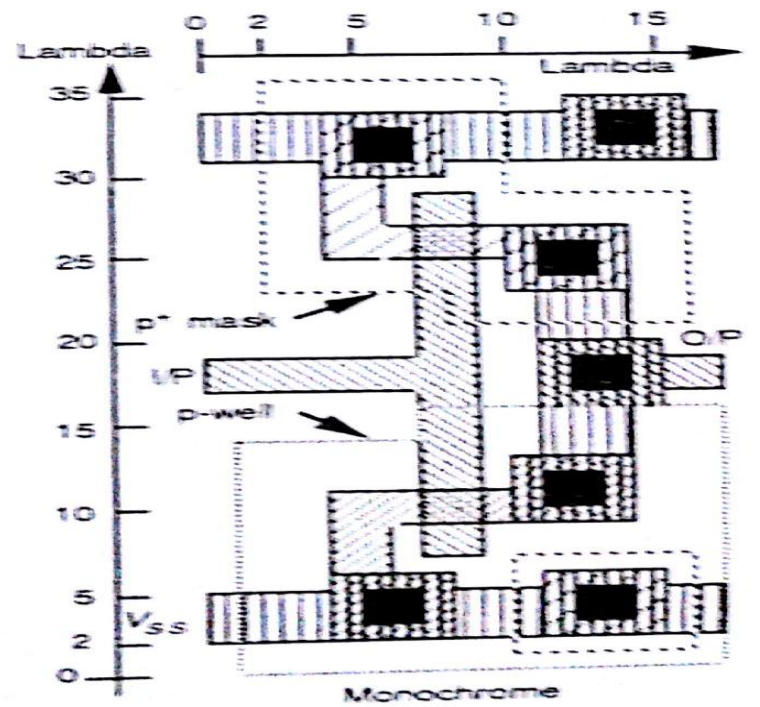
Stick diagram



Color fill



Color hatching



Monochrome

COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER
	MONOCHROME		MONOCHROME	
GREEN		[n-diffusion (n ⁺ active) Thinox *]		ND
RED		Polysilicon		NP
BLUE		Metal 1		NM
BLACK		Contact cut		NC
GRAY	NOT APPLICABLE	Overglass		NG
nMOS ONLY YELLOW		Implant		NI
nMOS ONLY BROWN		Buried contact		NB
FEATURE	FEATURE (STICK) (MONOCHROME)	FEATURE (SYMBOL) (MONOCHROME)	FEATURE (MASK) (MONOCHROME)	
<i>n</i> -type enhancement mode transistor				
Transistor length to width ratio L:W should be shown but source, drain and gate labeling will not normally be shown.				
<i>n</i> -type depletion mode transistor nMOS ONLY				

FIGURE 3.1(a) Encodings for a simple metal nMOS process (see Color plate 1(a) for nMOS color encoding details).

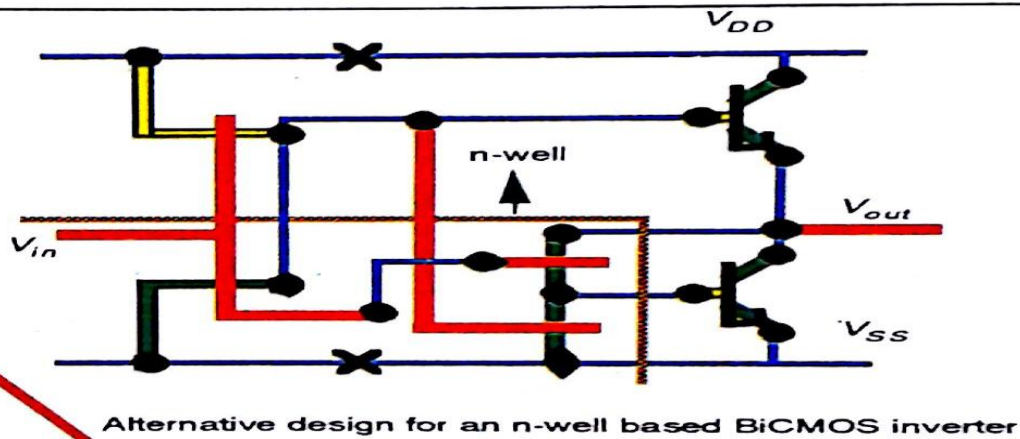
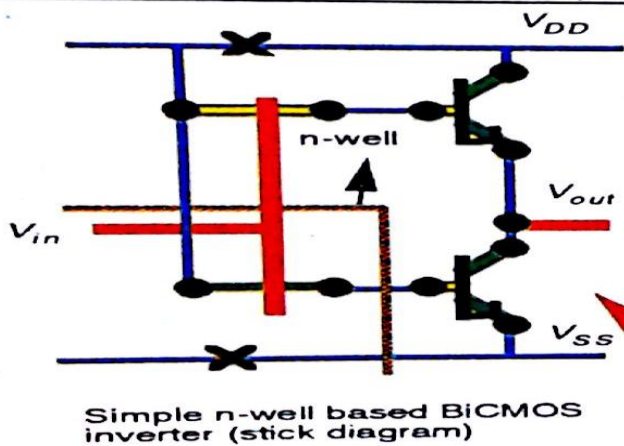
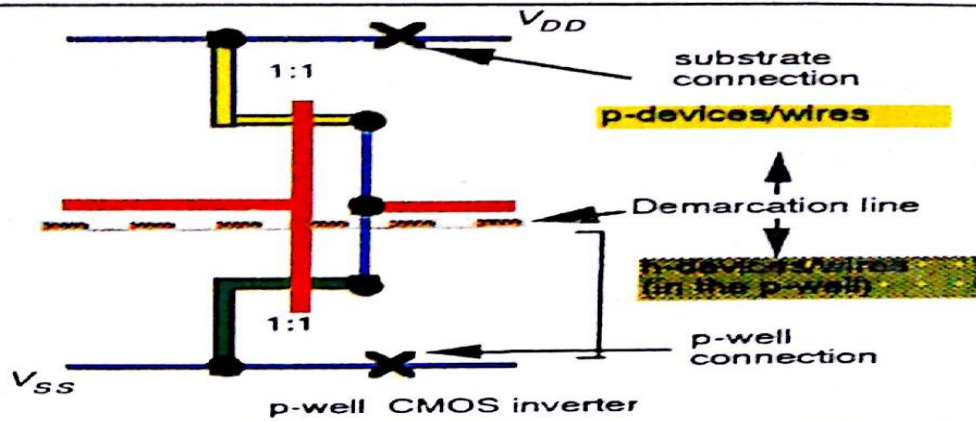
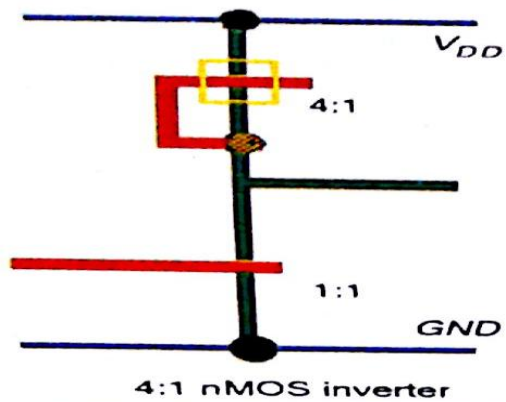
COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER	
GREEN	MONOCHROME ENCODING AS IN FIGURE 3-1(a)	n-diffusion (n+ active) Thinox Polysilicon Metal 1 Contact cut Overglass	MONOCHROME * Thinox = n-diff. + p-diff. + transistor channels		CAA or CNA
RED			ENCODING AS IN FIGURE 3-1(a)	CPF	
BLUE				CMF	
BLACK				CC	
GRAY				COG	
GREEN IN P+ (MASK)	NOT SHOWN IN STICK DIAGRAM	p-diffusion (p+ active)		CAA or CPA	
YELLOW (STICK)		p+ mask		CPP	
YELLOW	DEMARCATIION LINE	Metal 2		CMS	
DARK BLUE OR PURPLE		VIA		CVA	
BLACK*		p-well		CPW	
BROWN	p-well edge is shown as a demarcation line in stick diagrams	VDD or VSS CONTACT		CC	
BLACK					
FEATURE	FEATURE (STICK) (MONOCHROME)	FEATURE (SYMBOL) (MONOCHROME)	FEATURE (MASK) (MONOCHROME)		
<i>n</i> -type enhancement mode transistor (as in Figure 3-1(a)) Transistor length to width ratio L:W may be shown.					
<i>p</i> -type enhancement mode transistor					

The same well encoding and demarcation line are used for an n-well process. For p-well process, the n features are in the well. For an n-well process, the p features are in the well.

COLOR	STICK ENCODING	LAYERS	MASK LAYOUT ENCODING	CIF LAYER
ORANGE	MONOCHROME	Polysilicon 2	MONOCHROME	CPS
SEE COLOR PLATE 1(c)		Bipolar npn transistor	see Figure 3-13(f)	Not applicable
PINK	Not separately encoded	p-base of bipolar npn transistor		CBA
PALE GREEN	Not separately encoded	Buried collector of bipolar npn transistor	n-well	CCA
FEATURE	FEATURE (STICK) (MONOCHROME)	FEATURE (SYMBOL) (MONOCHROME)	FEATURE (MASK) (MONOCHROME)	
<i>n</i> -type enhancement poly. 2 transistor Transistor length to width ratio L:W may be shown.				
<i>p</i> -type enhancement poly. 2 transistor <i>Note:</i> p-type transistors are placed above and n-type transistors below the demarcation line.				
<i>n</i> pn bipolar transistor			See Figure 3-13(f) and Color plate 6	

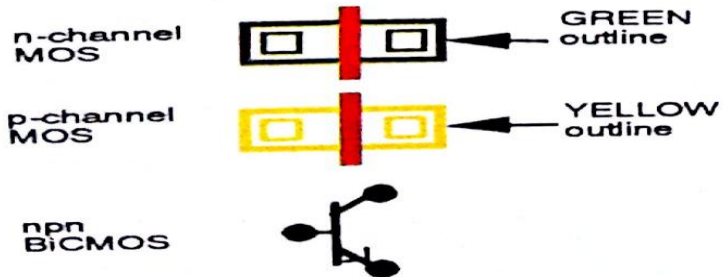
The same well encoding and demarcation line as in Figure 3-1(b) are used for an n-well process. For a p-well process, the n features are in the well. For an n-well process, the p features are in the well.

FIGURE 3.1(c) Additional encodings for a double metal double poly. BiCMOS n-well process (see Color plates 1(c) and 6 for additional CMOS and BiCMOS color encoding details).

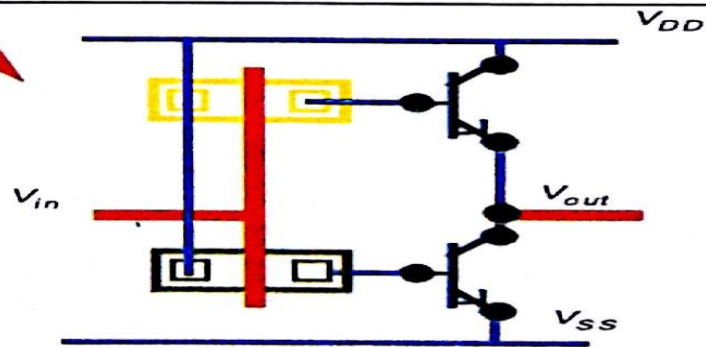


Simple symbolic notation

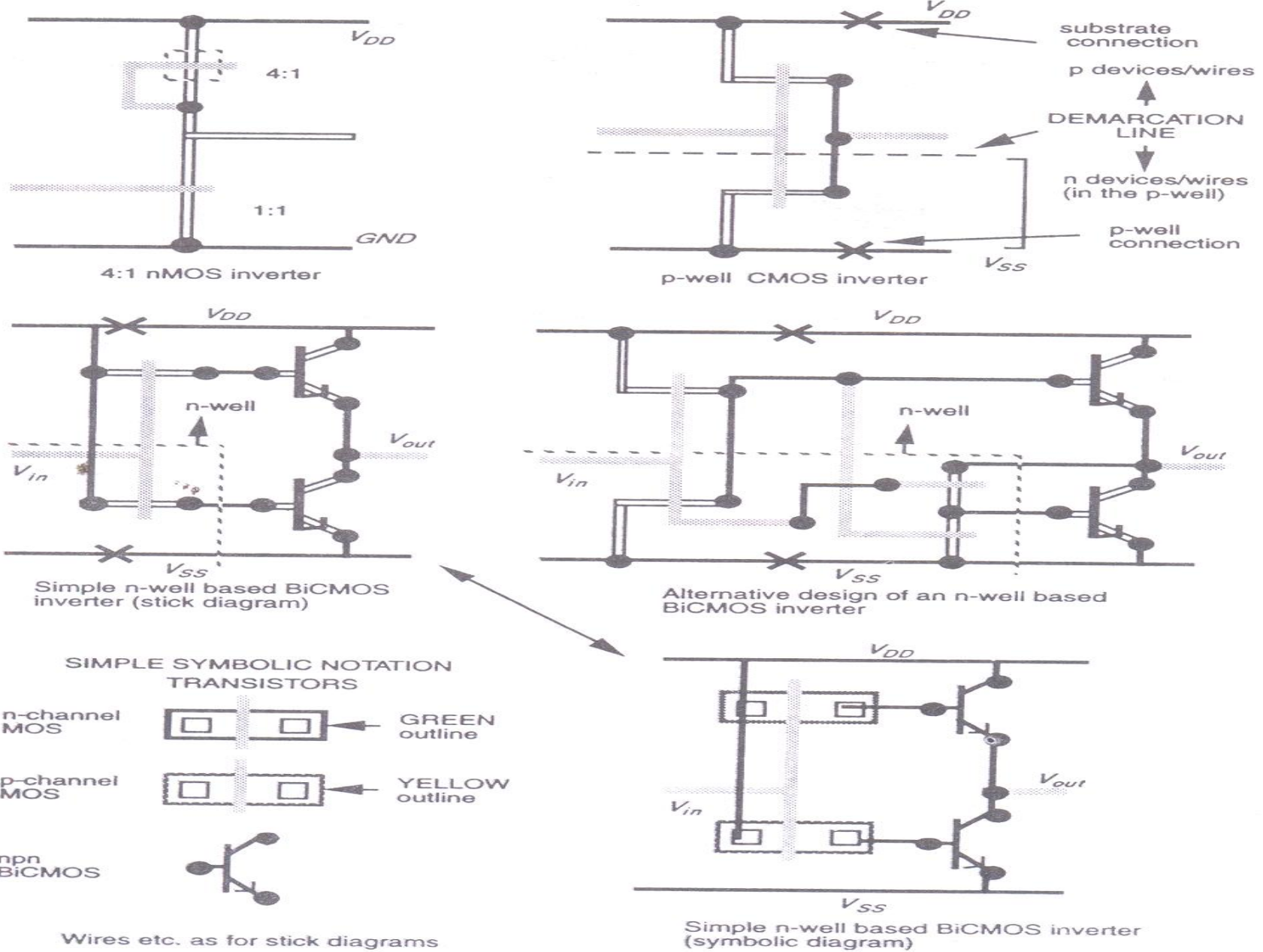
Transistors



WIRES etc., as for stick diagrams



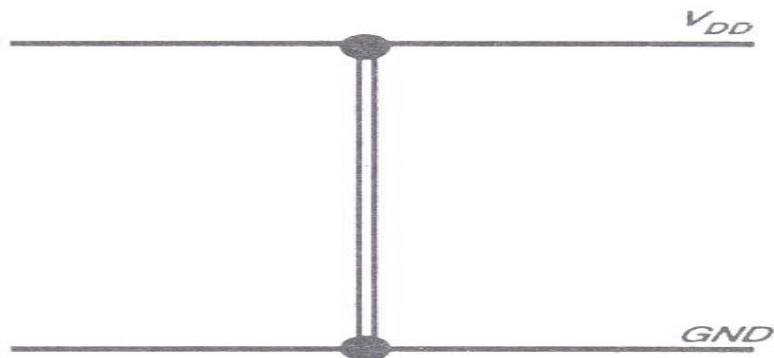
COLOR PLATE 1(d) Color stick diagram examples. (See Figure 3.1(d) monochrome stick diagrams and simple symbolic encoding.)



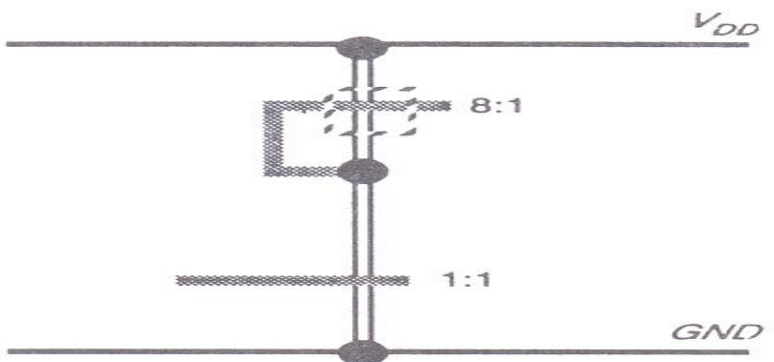
Monochrome stick diagram examples

FIGURE 3.1(d) Stick diagrams and simple symbolic encoding (see also Color plate 1(d)).

(i) Shift register cell

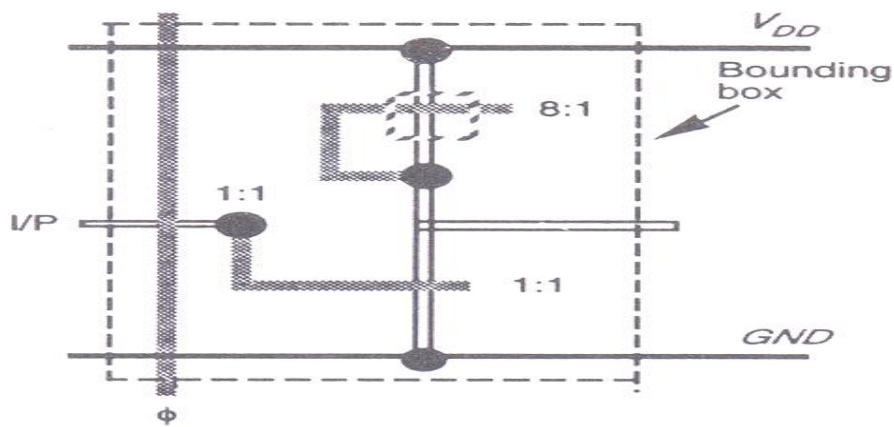
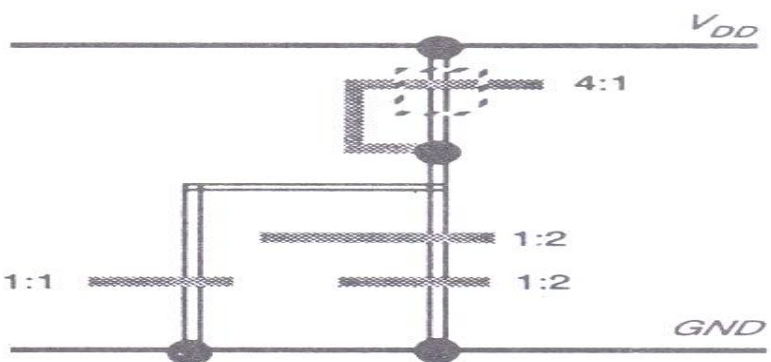
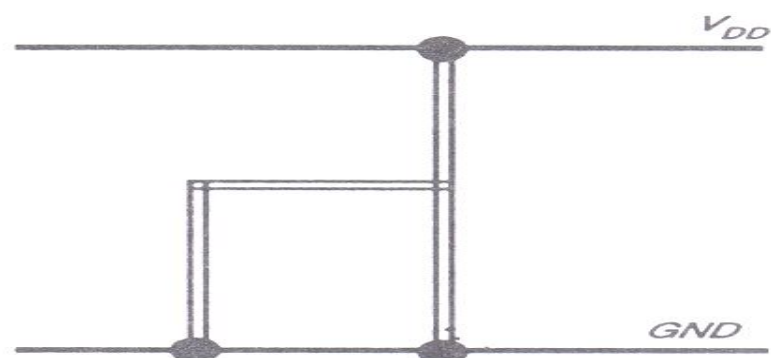


(a) Rails and thinox paths



(b) Pull-up and pull-down structures (polysilicon), implants, and ratios

(ii) Logic function $\bar{X} = A + B.C$



(c) Buses, control signals, interconnections, and 'leaf-cell' boundaries

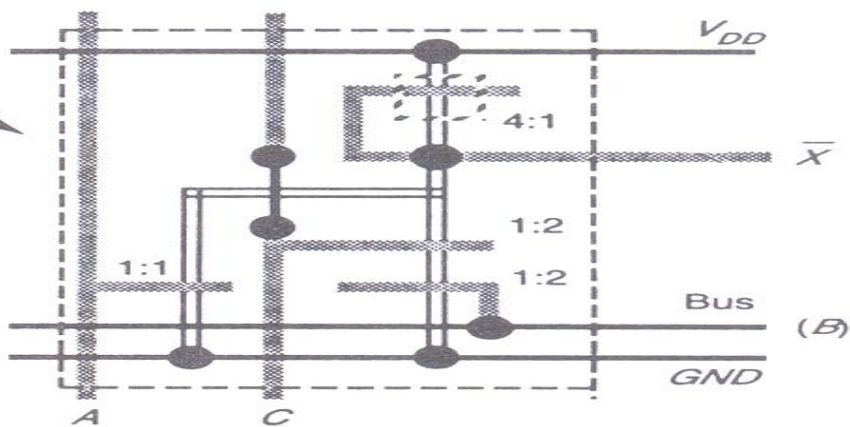
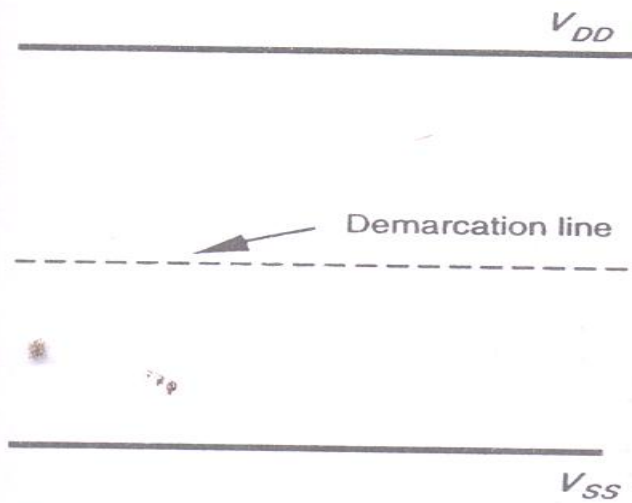
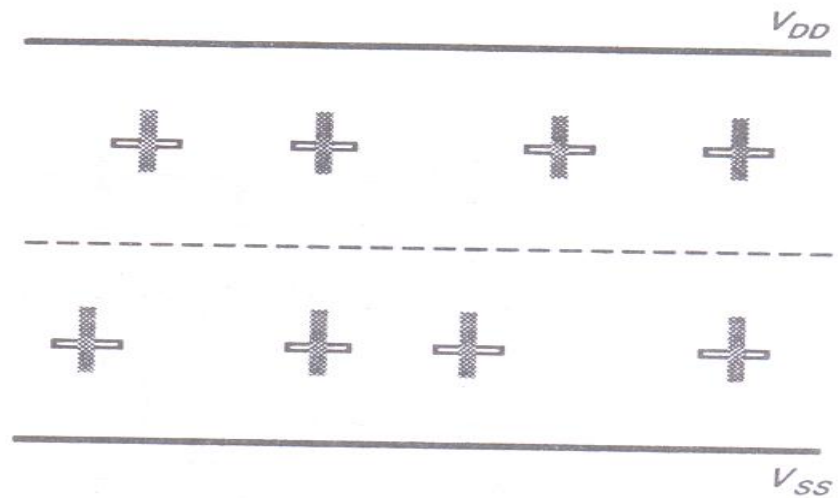


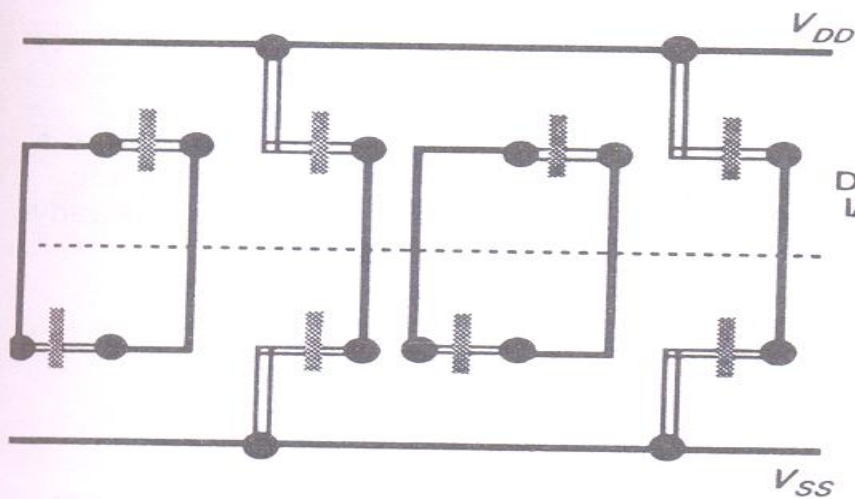
FIGURE 3.3 Examples of nMOS stick layout design style.



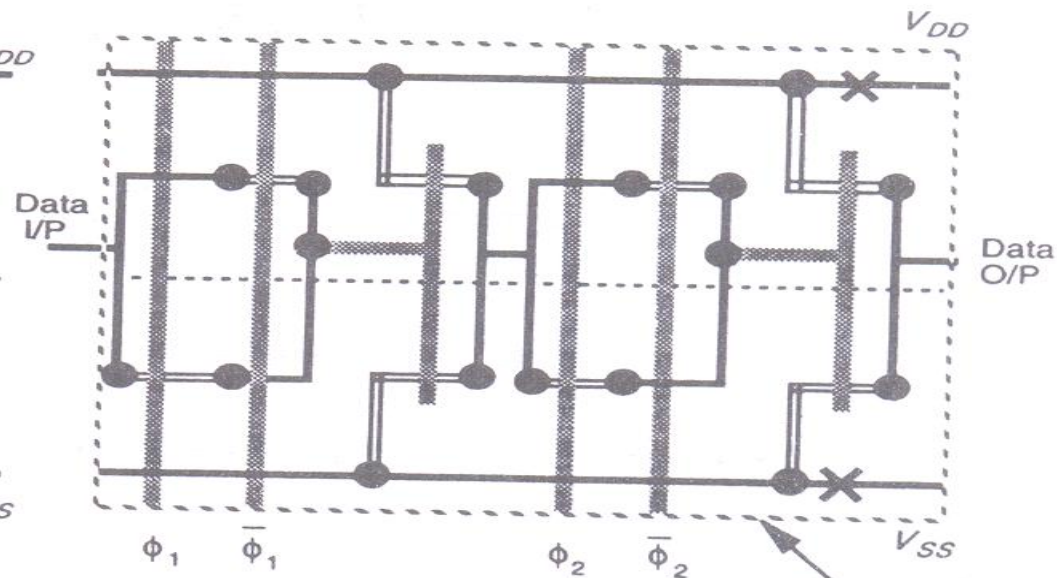
(a) Rails and demarcation line



(b) n- and p-transistors



(c) Metal and diffusion connections



(d) Remaining interconnections

Note: The contact crosses in (d) should represent one V_{DD} contact for every four p-transistors and one V_{SS} contact for every four n-transistors.

FIGURE 3.5 Example of CMOS stick layout design style.

Design Rules and Layout

The object of a set of design rules is to allow a ready translation of circuit design concepts, usually in stick diagram or symbolic form into actual geometry in silicon.

The design rules basically address two issues:

1. The interactions between different layers.
2. The geometrical reproduction of features that can be reproduced by the mask-making and lithographical process.

Lambda based Design Rules:

1. The lambda based design rule specify every dimension of a system in terms of a parameter λ which is subsequently assigned a value, such that the features resulting out of the design are supported by the fabrication process.
2. Defining lambda makes design independent of process therefore chip can be scaled to any ratio that means today's design remain usable when line widths are reduced(λ) by advances in future technology.
3. Under these rules, all dimensions in all layers will be dimensioned in λ units and after that λ is given an appropriate value acceptable to the feature size of the fabrication process

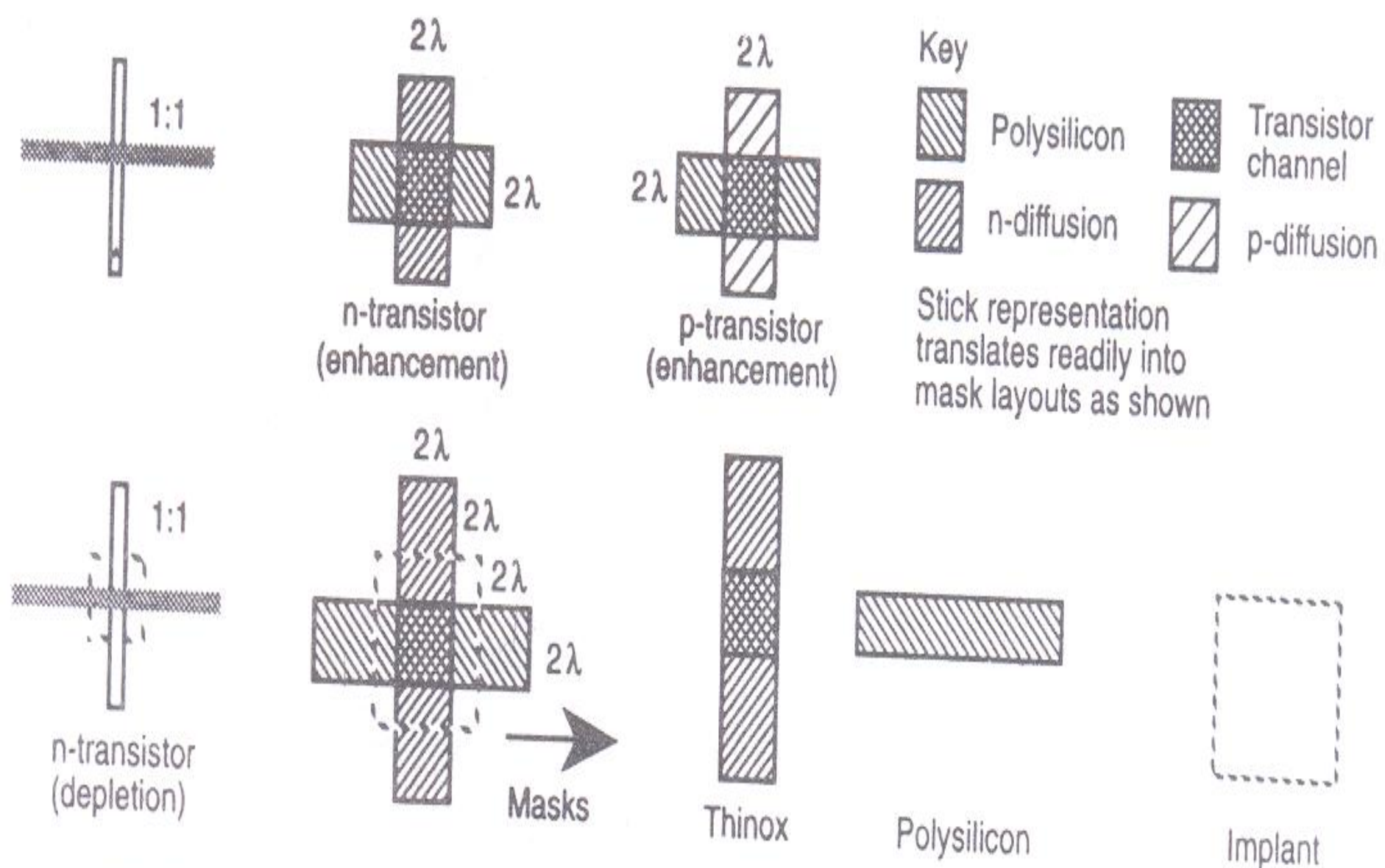


FIGURE 3.2 Stick diagrams and corresponding mask layout examples.

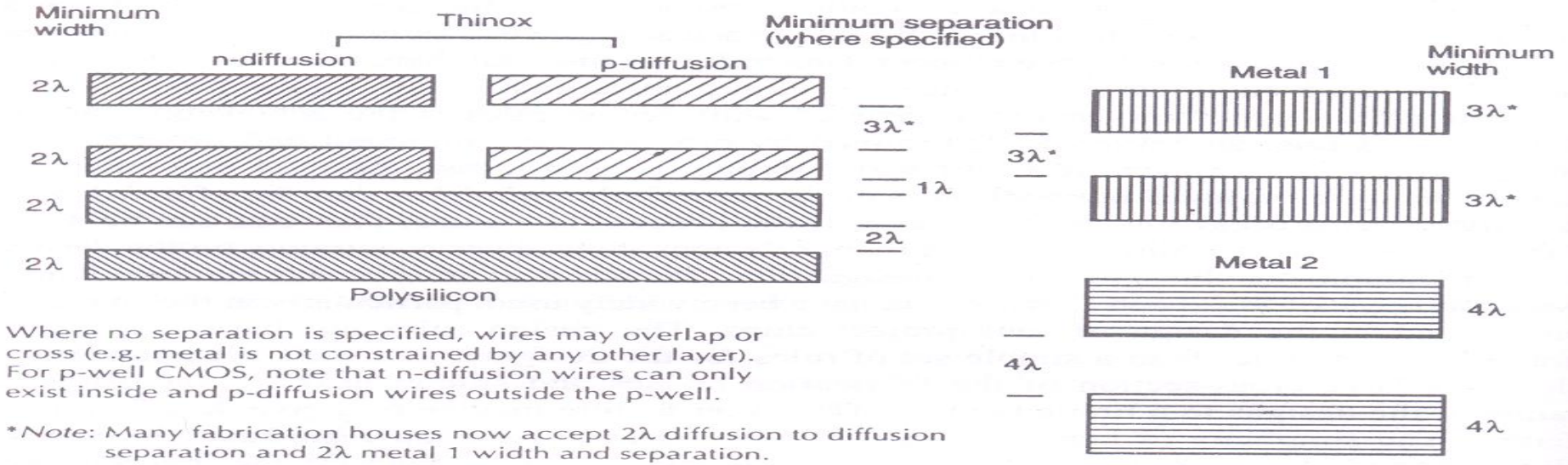


Figure 3-6 Design rules for wires (nMOS and CMOS)

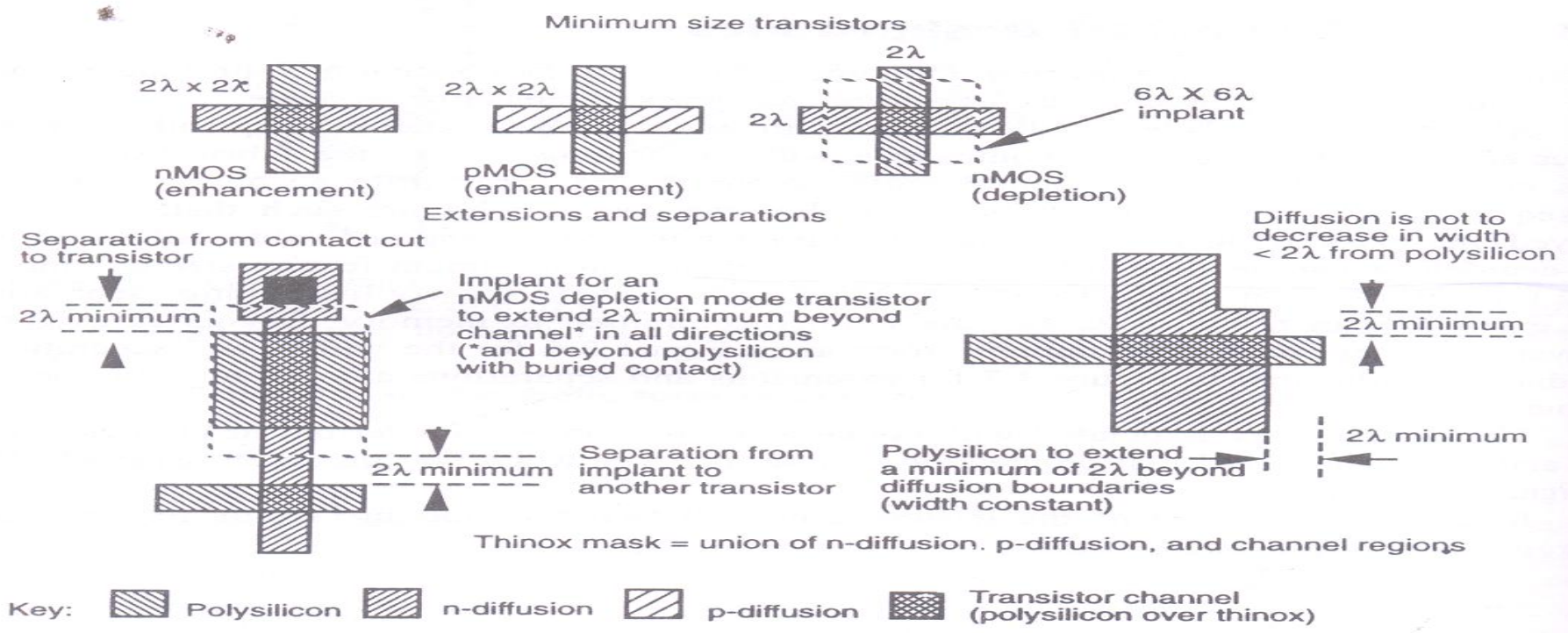
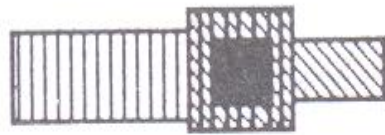


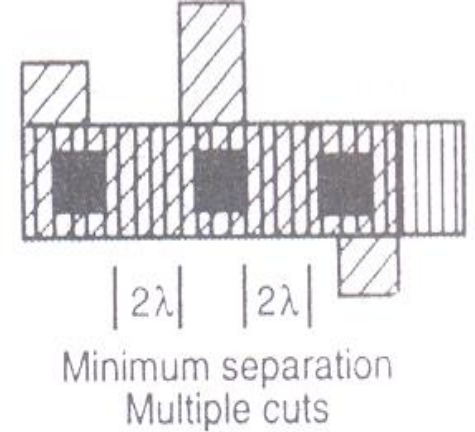
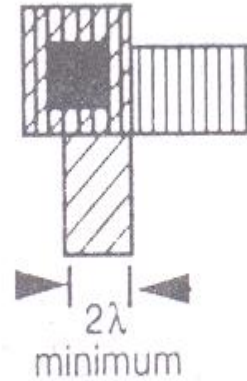
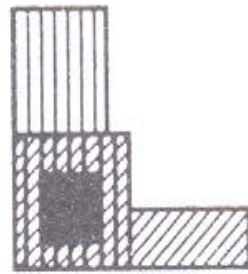
FIGURE 3.7 Transistor design rules (nMOS, pMOS and CMOS).

1. Metal 1 to polysilicon or to diffusion

3λ minimum

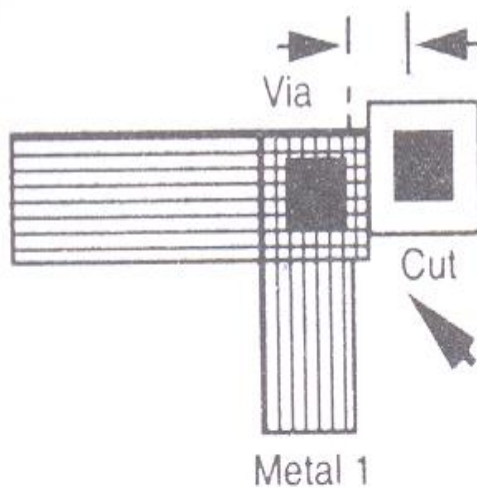


$2\lambda \times 2\lambda$ cut centered on $4\lambda \times 4\lambda$ superimposed areas of layers to be joined in all cases



2. Via (contact from metal 2 to metal 1 and thence to other layers)

Metal 2



2λ minimum separation (if other spacings allow)

$4\lambda \times 4\lambda$ area of overlap with $2\lambda \times 2\lambda$ via at center

Metal 1

Via and cut used to connect metal 2 to diffusion

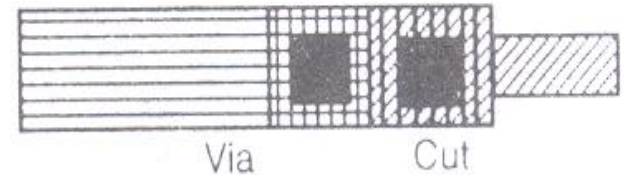


FIGURE 3.8 Contacts (nMOS and CMOS).

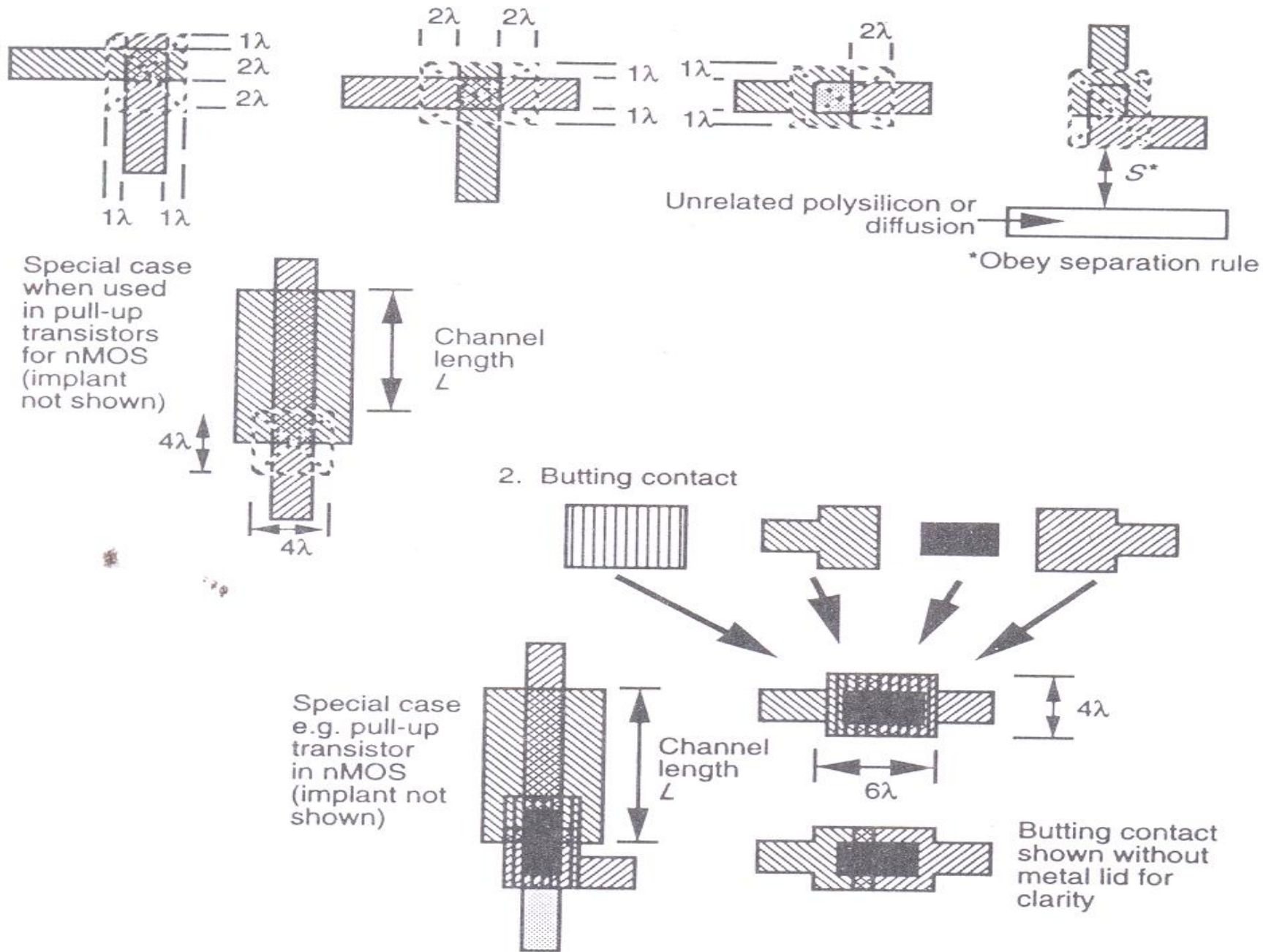
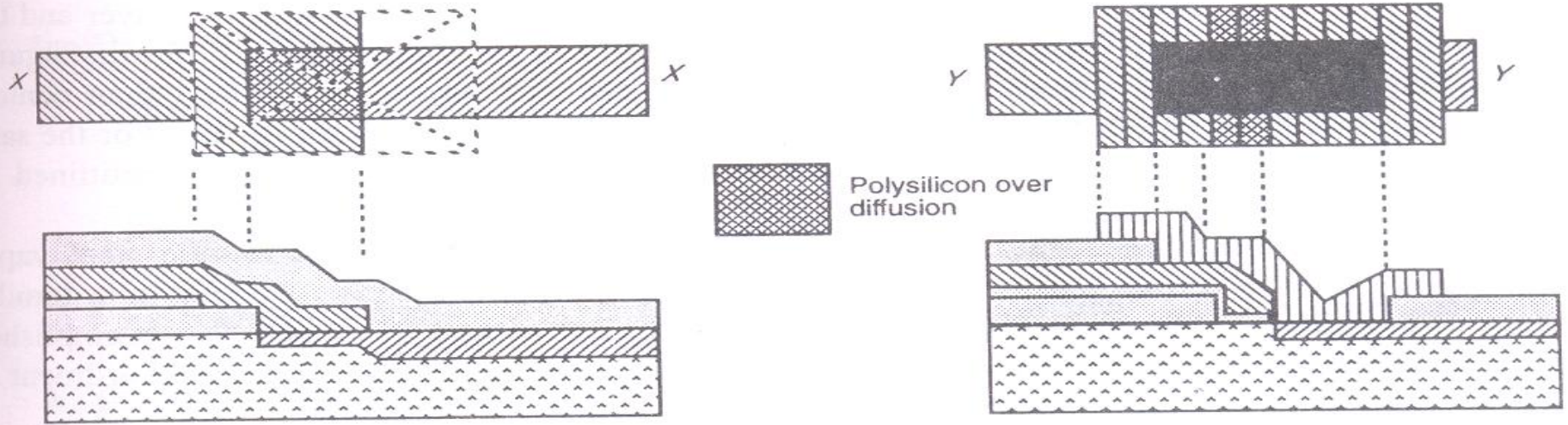


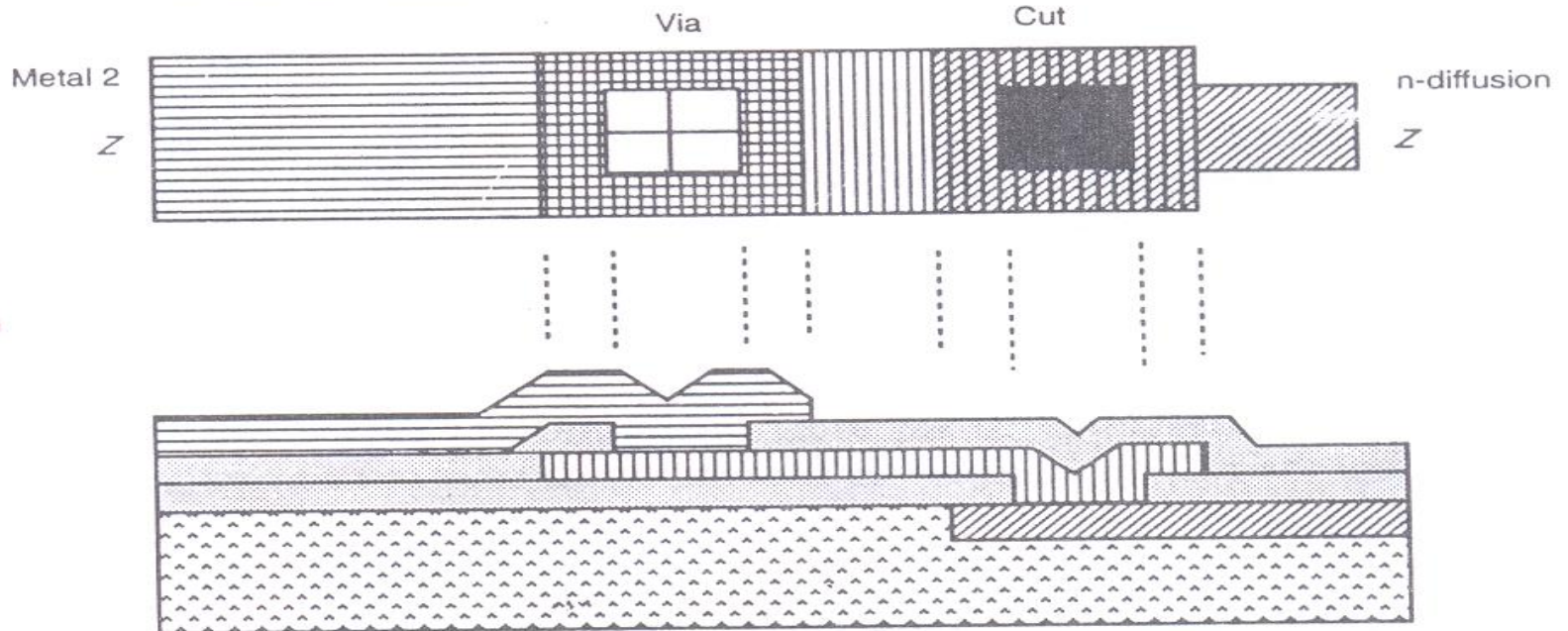
FIGURE 3.9 Contacts polysilicon to diffusion (nMOS only in the main text).



(a) Buried contact . . . section through XX

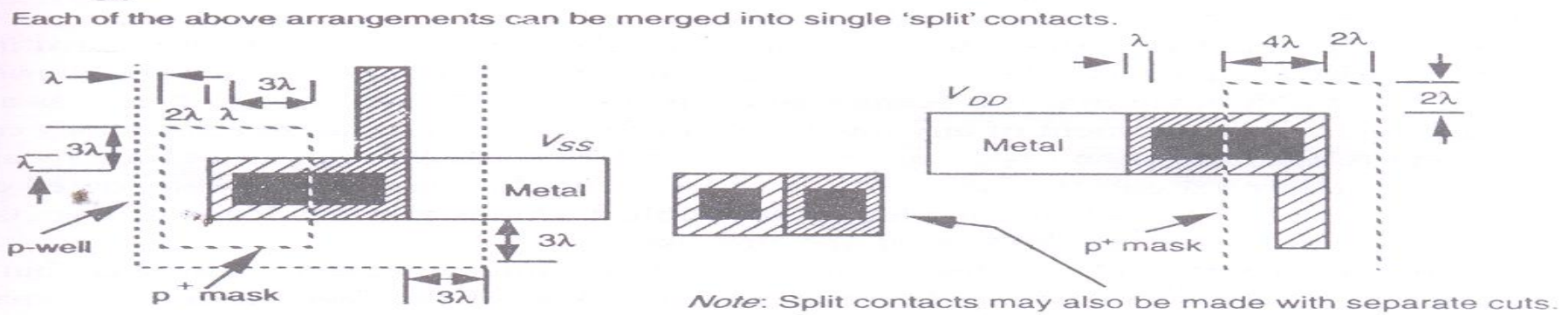
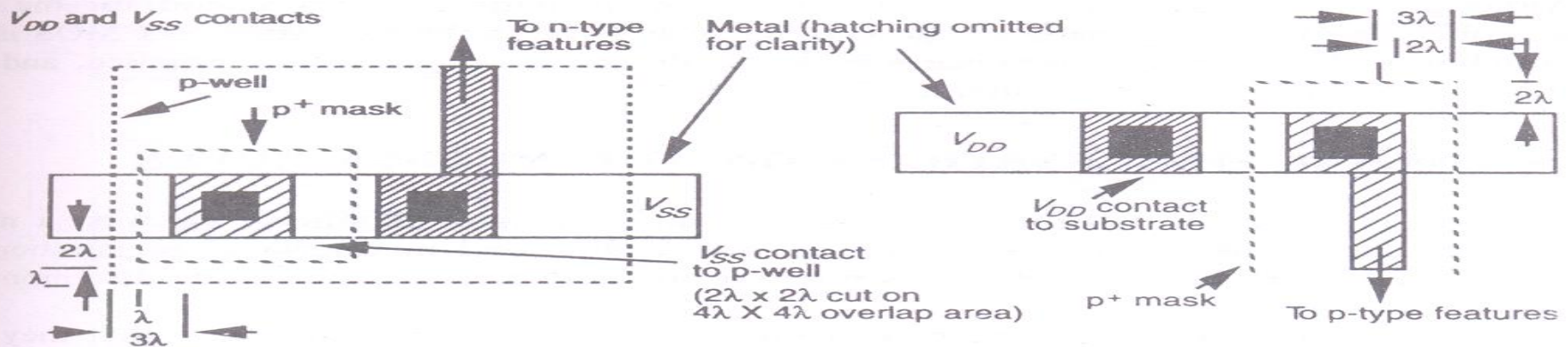
(b) Butting contact . . . section through YY

Contact from metal 2 to n-diffusion (not using minimum spacing via to cut)



(c) Metal 2-via-metal 1-cut-n-diffusion connection . . . section through ZZ

FIGURE 3.10 Cross-sections through some contact structures.



p-well and p+ mask rules

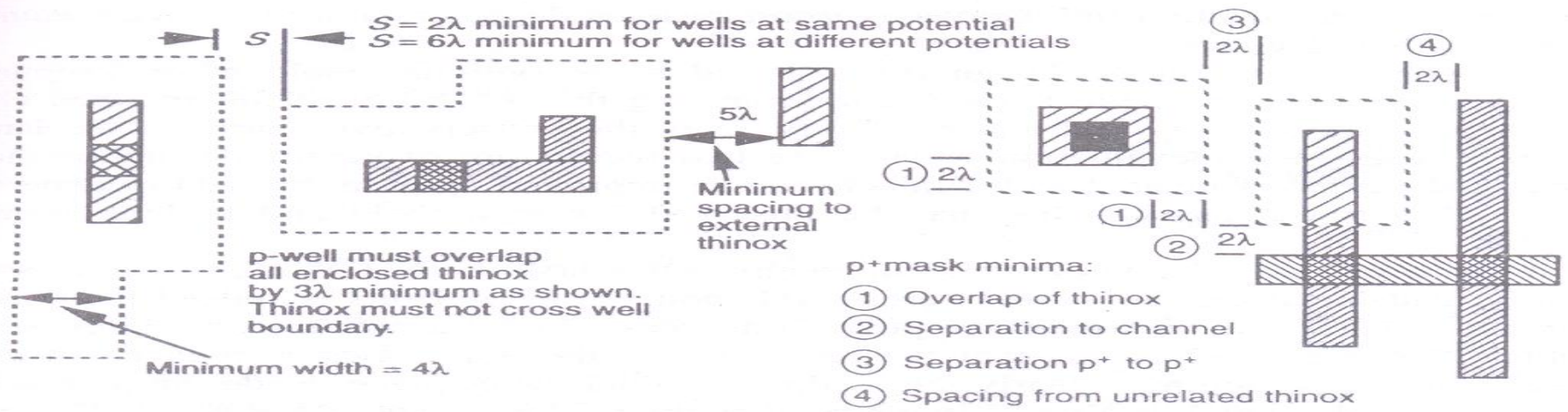
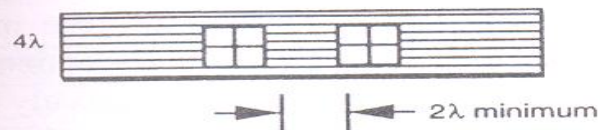
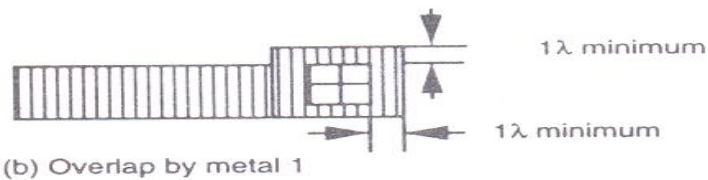


FIGURE 3.11 Particular rules for p-well CMOS process.

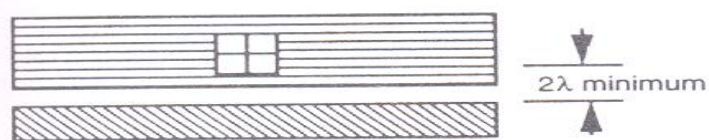
1. Aspects related to vias (double metal processes)



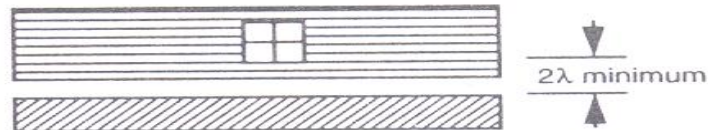
(a) Separation via to via



(b) Overlap by metal 1

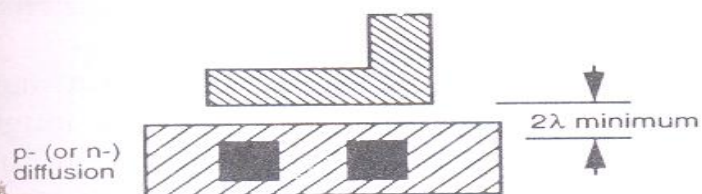


(c) Separation via to polysilicon

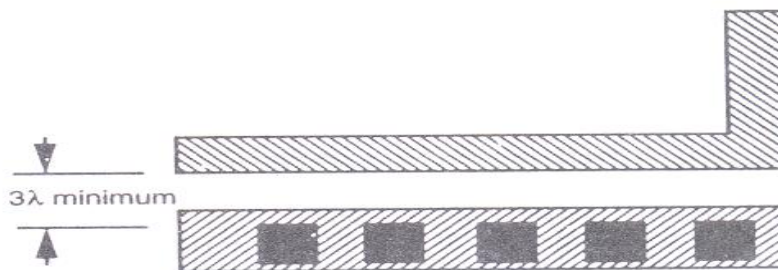


(d) Separation to thinox

2. Polysilicon wires separation from cuts

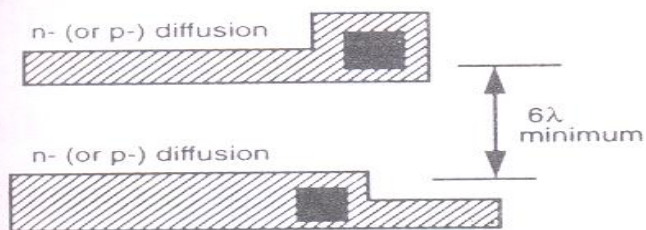


(a) Short polysilicon run

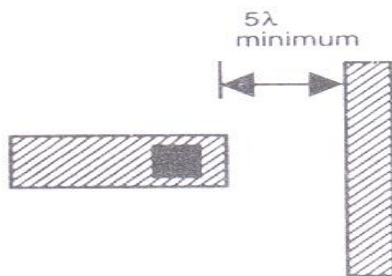


(b) Long polysilicon runs

3. Diffusion wires separation from cuts



Separations between different active areas



4. Increase in polysilicon overlap to reduce metal migration effect

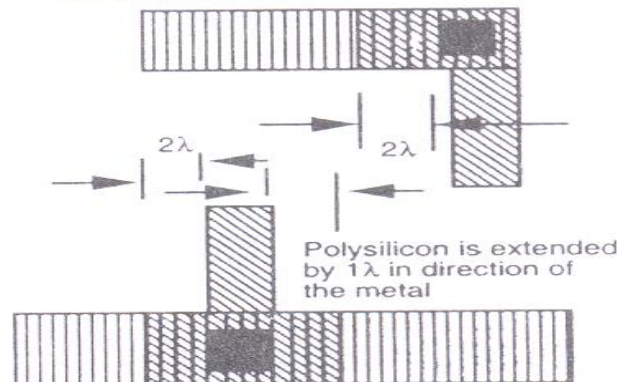
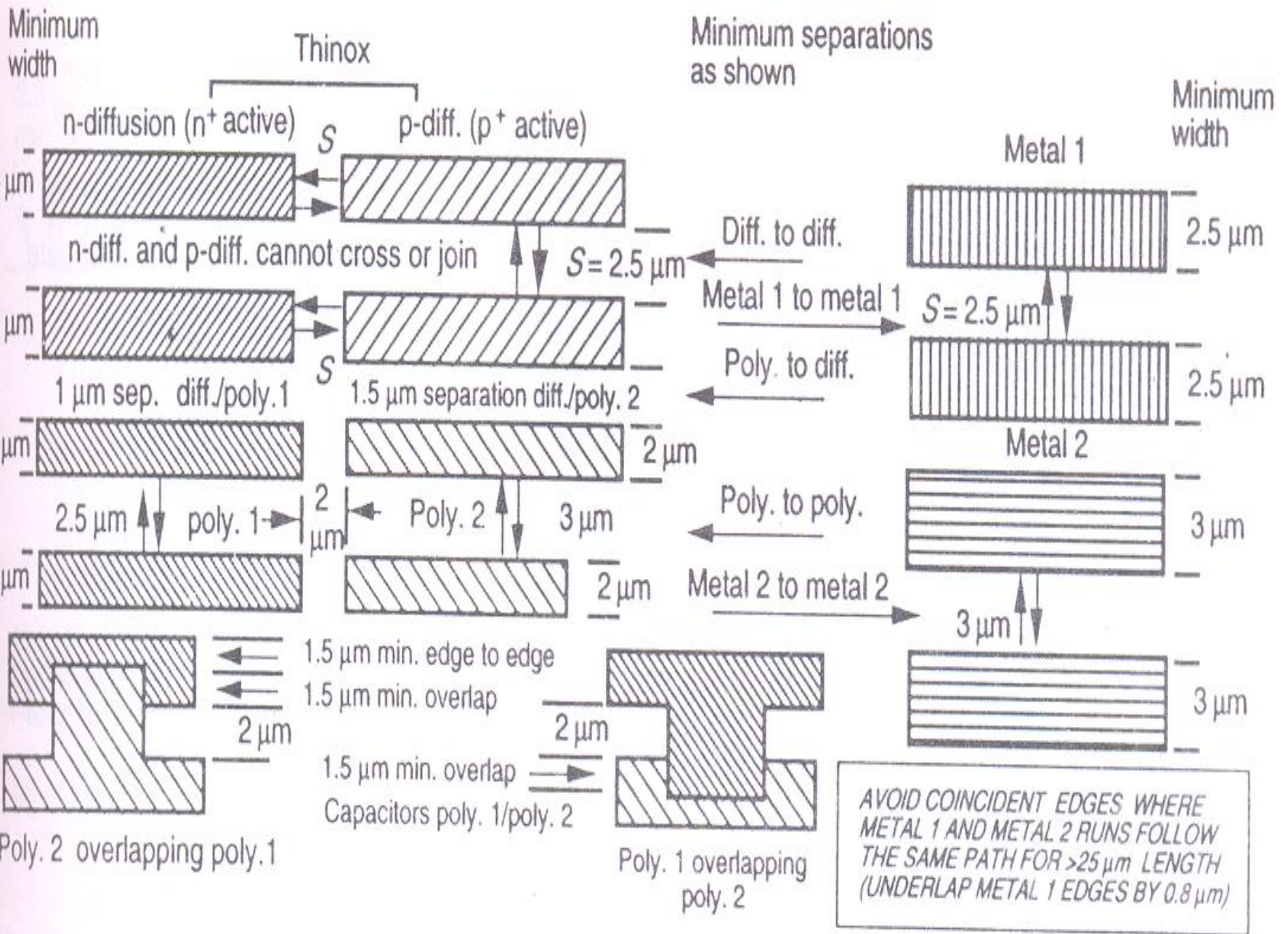


FIGURE 3.12 Further aspects of λ -based design rules for contacts, including some factors contributing to higher yield/reliability.



Otherwise polysilicon 2 must not be coincident with polysilicon 1

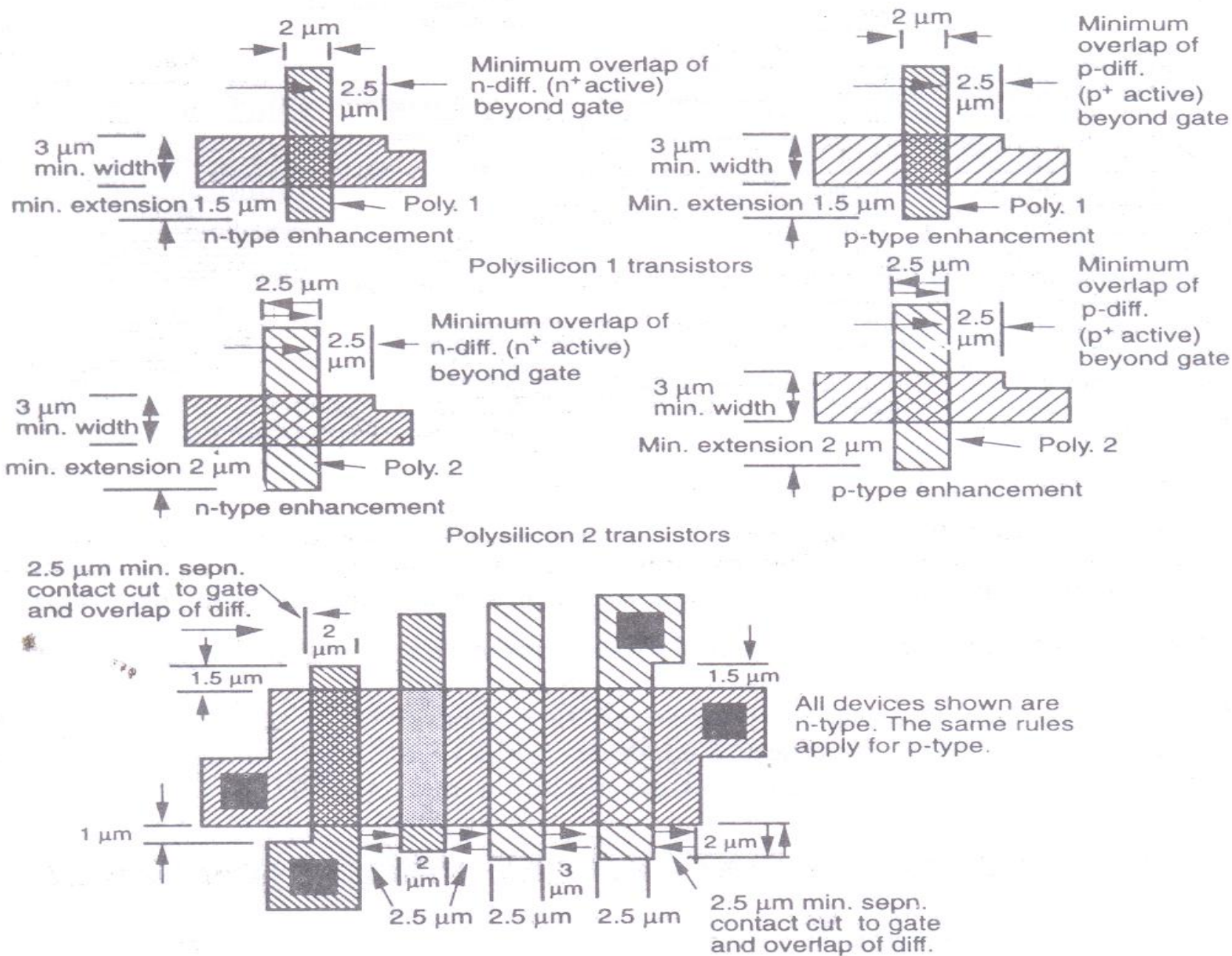
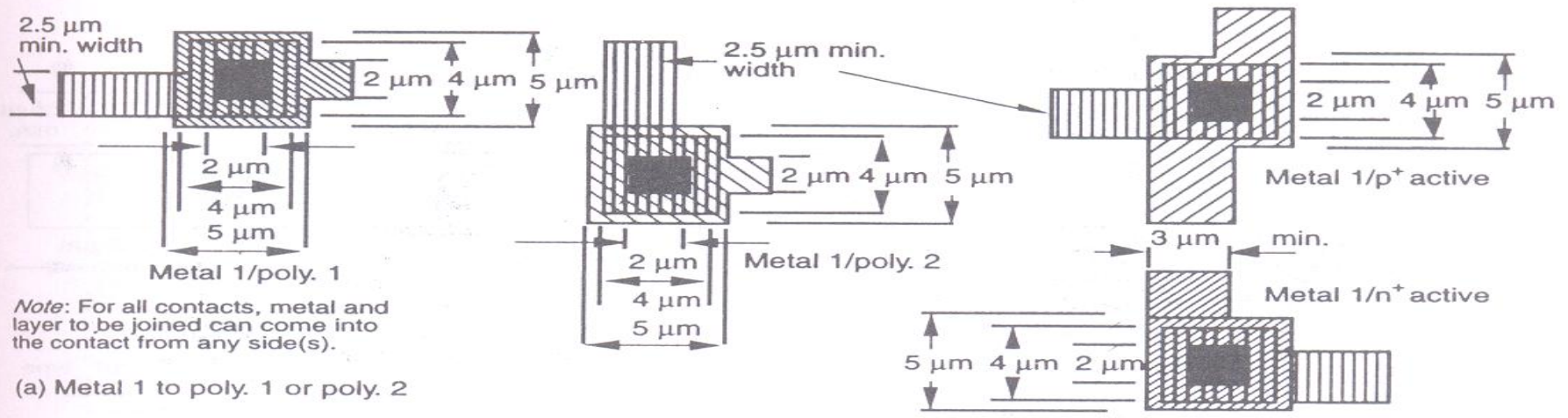


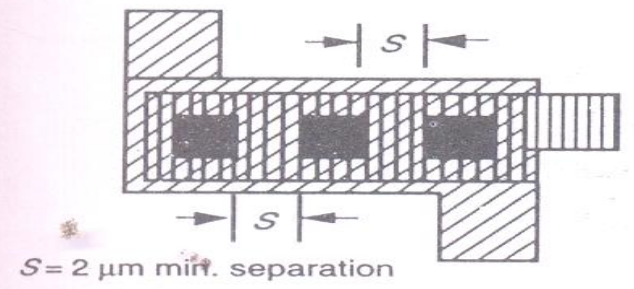
FIGURE 3.13(b) Transistor related design rules (Orbit $2\ \mu\text{m}$ CMOS) minimum sizes and overlaps



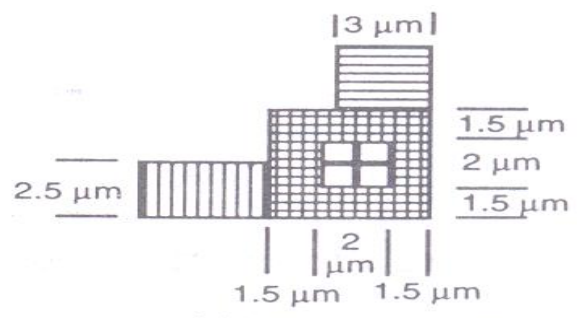
Note: For all contacts, metal and layer to be joined can come into the contact from any side(s).

(a) Metal 1 to poly. 1 or poly. 2

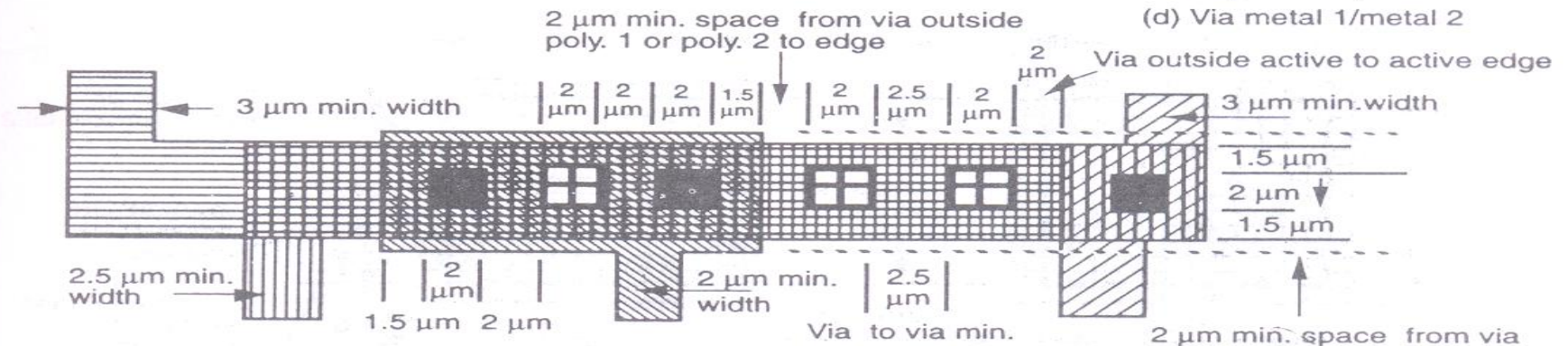
(b) Metal 1 to n⁺ or p⁺ active (diff.)



(c) Multiple contact cuts



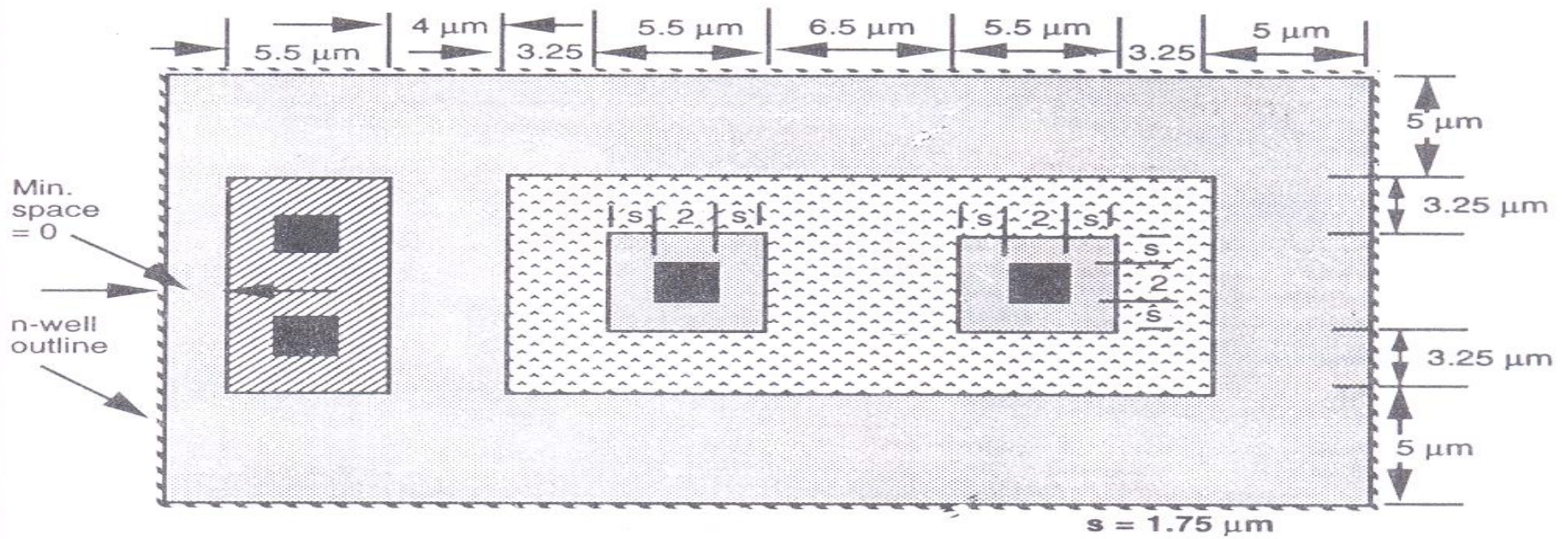
(d) Via metal 1/metal 2



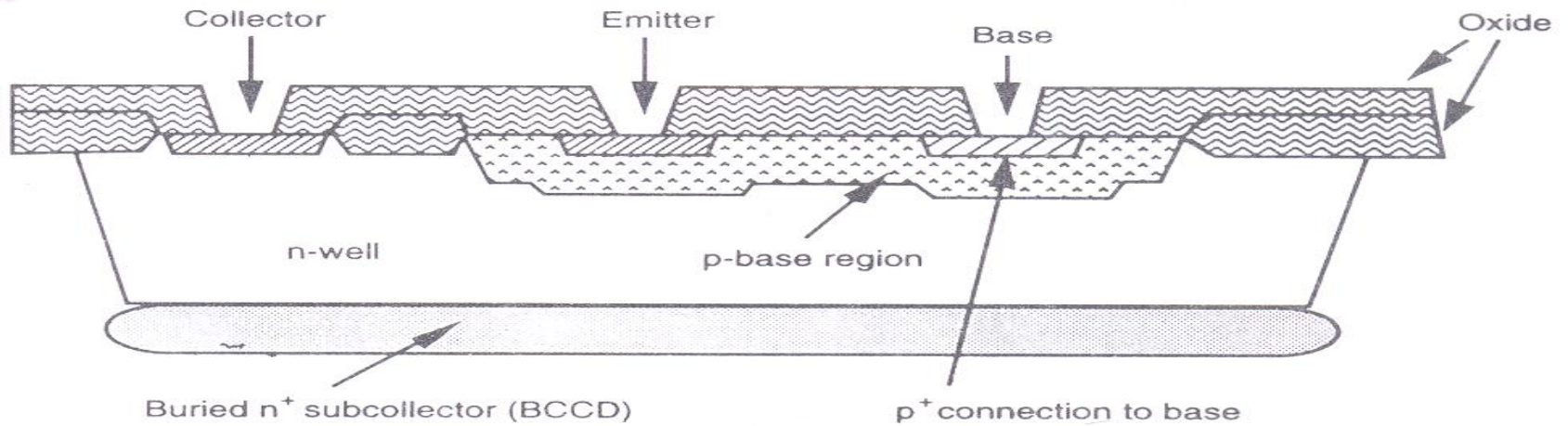
(e) Vias from metal 2 to metal 1 and thence to other layers

Note: The vias must not be placed over contacts

FIGURE 3.13(c) Rules for contacts and vias (Orbit 2 μm CMOS).



Note: For clarity, the layers have not been drawn transparent but BCCD underlies the entire area and the p-base underlies all within its boundary.



Cross-section through npn transistor (Orbit 2 μm BiCMOS)

FIGURE 3.13(f) Special rules for BiCMOS transistors (Orbit 2 μm CMOS).

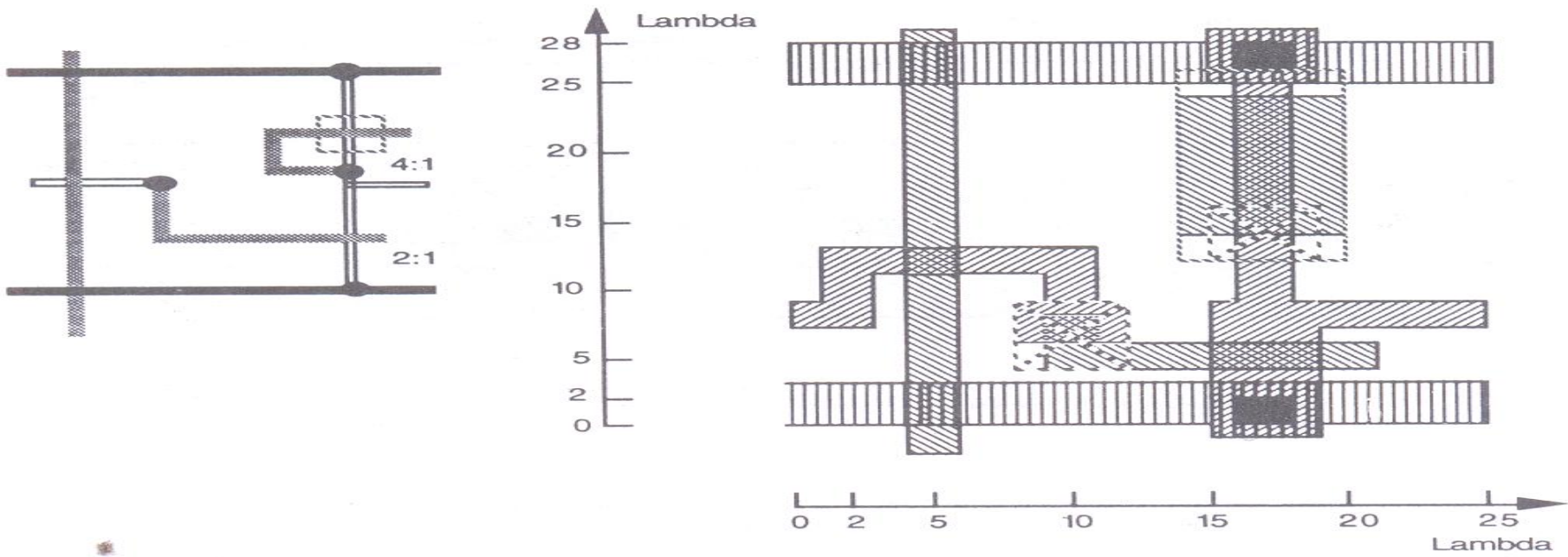


FIGURE 3.14 Stick diagram and layout for nMOS shift register cell.

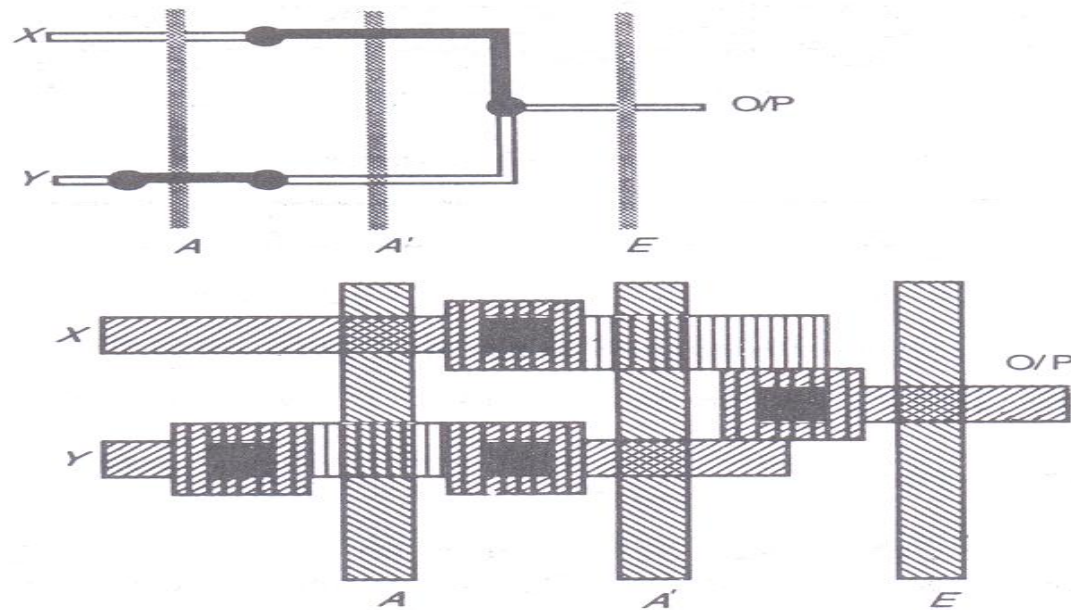


FIGURE 3.15 Two-way selector with enable.

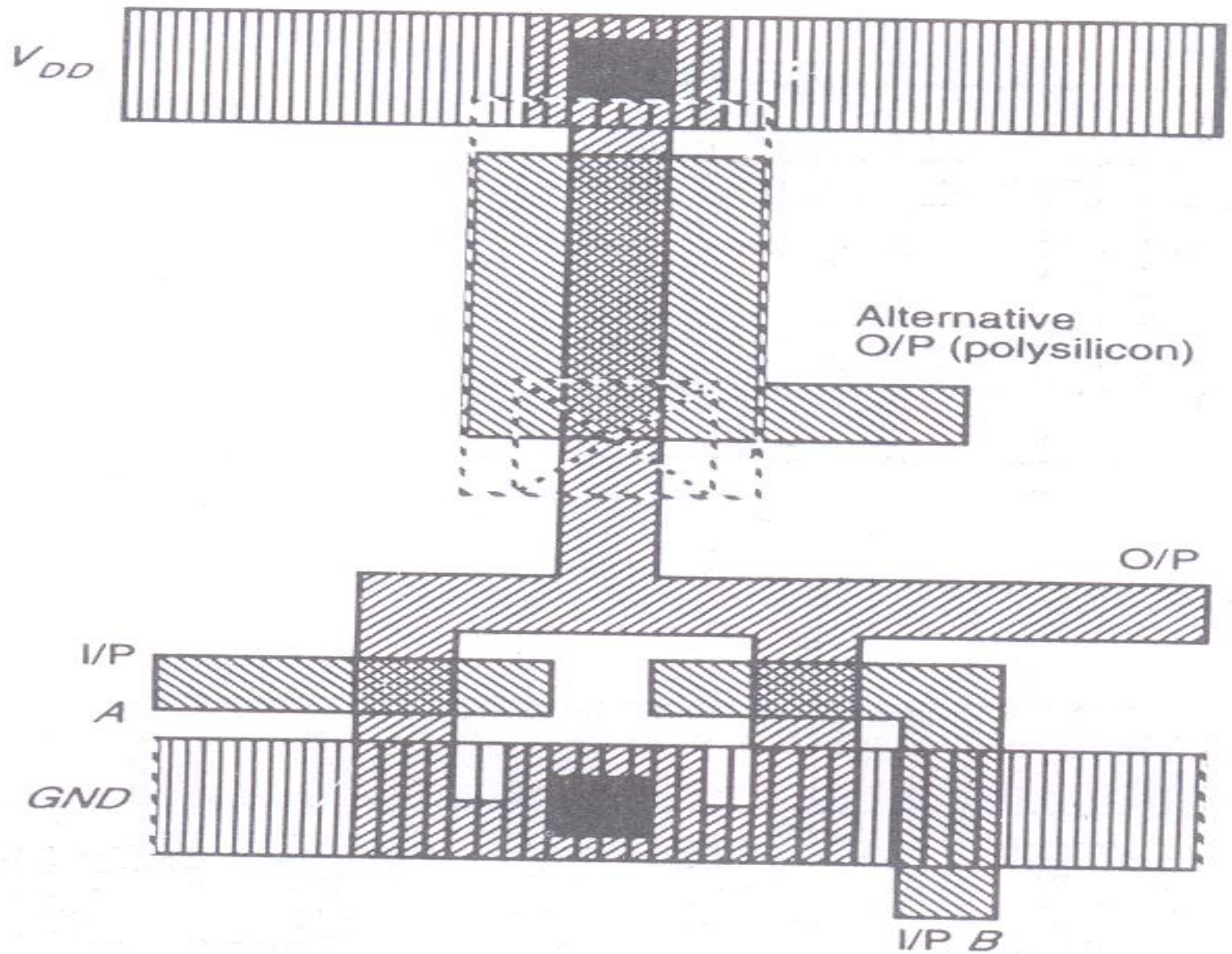


FIGURE 3.16 Two I/P nMOS *Nor* gate.

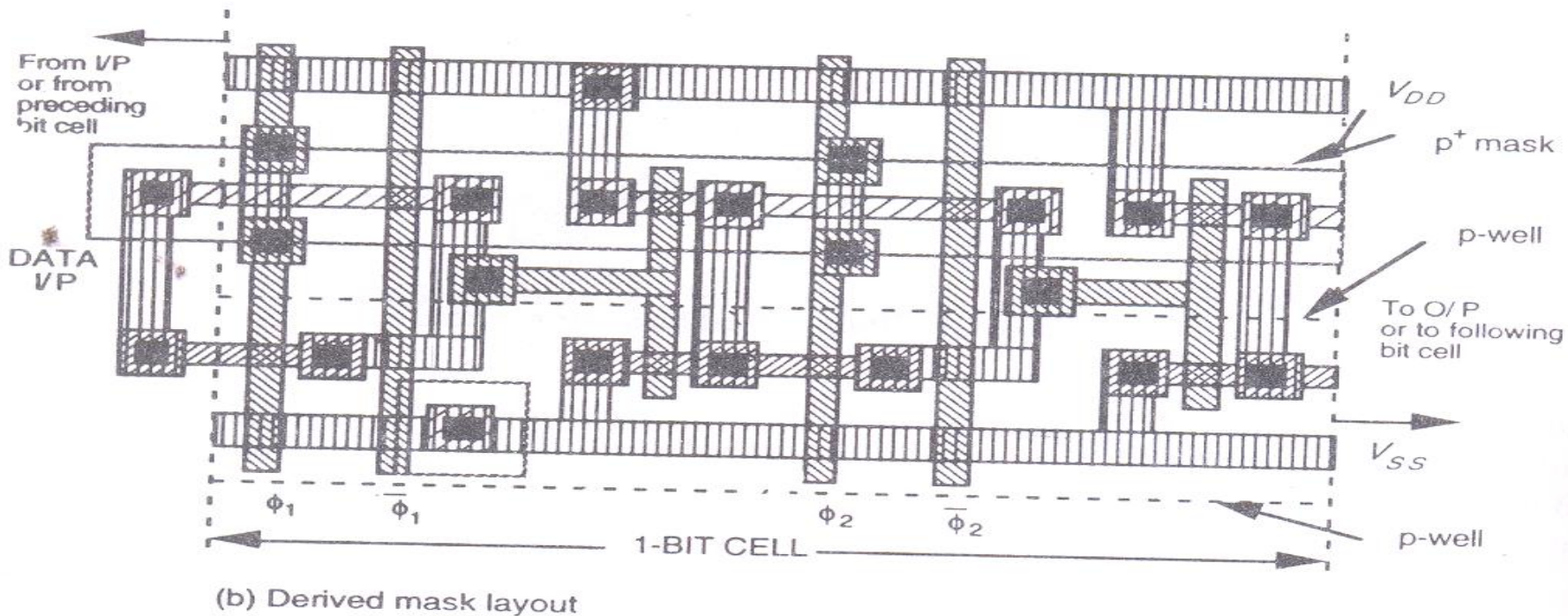
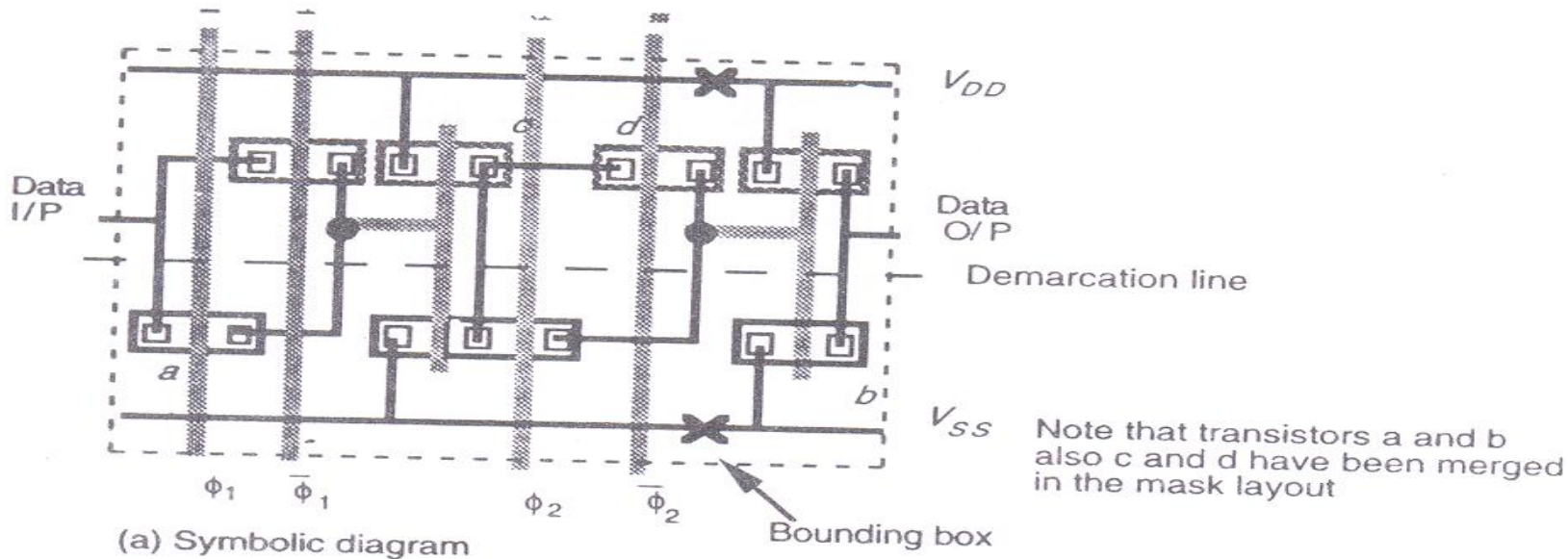


FIGURE 3.17 A 1-bit CMOS shift register cell.

Queries?

